

**19th TREDI Workshop on Advanced
Silicon Radiation Detectors**

**FBK NUV-HD SiPMs with metal-filled trenches:
from simulations to timing performances**

Turin, 20-22 February 2024

M. Penna^{1,2}, F. Acerbi¹, J. Dalmasson¹, A. Ficorella¹, M. Goano²,
S. Merzi¹, E. Moretti¹, M. Ruzzarin¹, O. M. Villareal¹, N. Zorzi¹, A. Gola¹

1. *Fondazione Bruno Kessler, Trento, Italy*
2. *Politecnico di Torino, Turin, Italy*

mpenna@fbk.eu
michele_penna@polito.it

FBK NUV-HD-MT SiPMs: simulations and timing performances

Outline

Introduction

- SiPM overview and NUV-HD-MT technology

Timing Performances

- Single Photon Time Resolution (SPTR)

SPAD signal electrical simulations

- SPAD equivalent electrical circuit
- Electrical parameters extraction
- Improved SPICE model

Conclusions and next steps

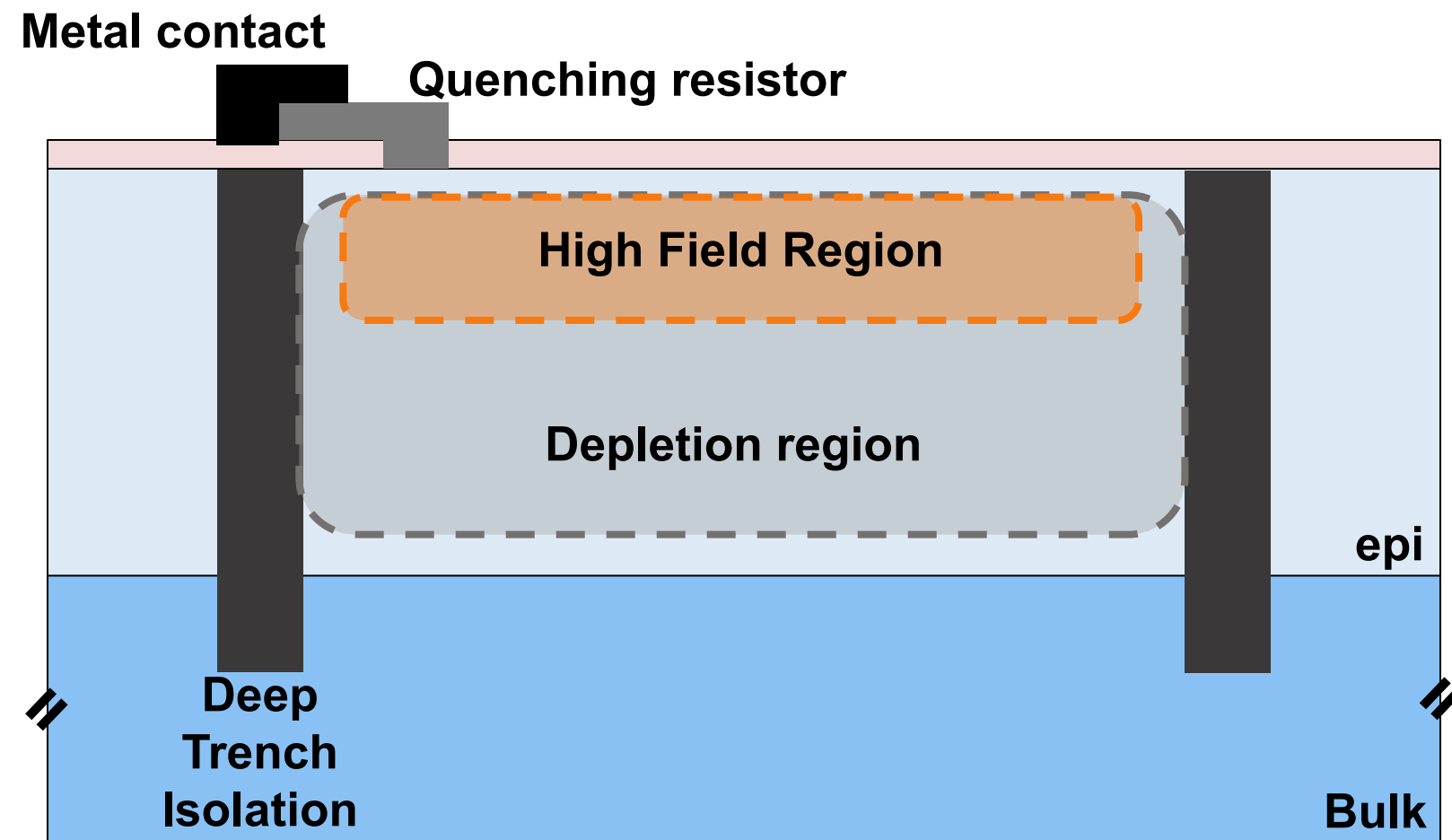


Introduction



Introduction

Single Photon Avalanche Diode (SPAD)



p-n junction biased above the breakdown voltage (V_{bd})

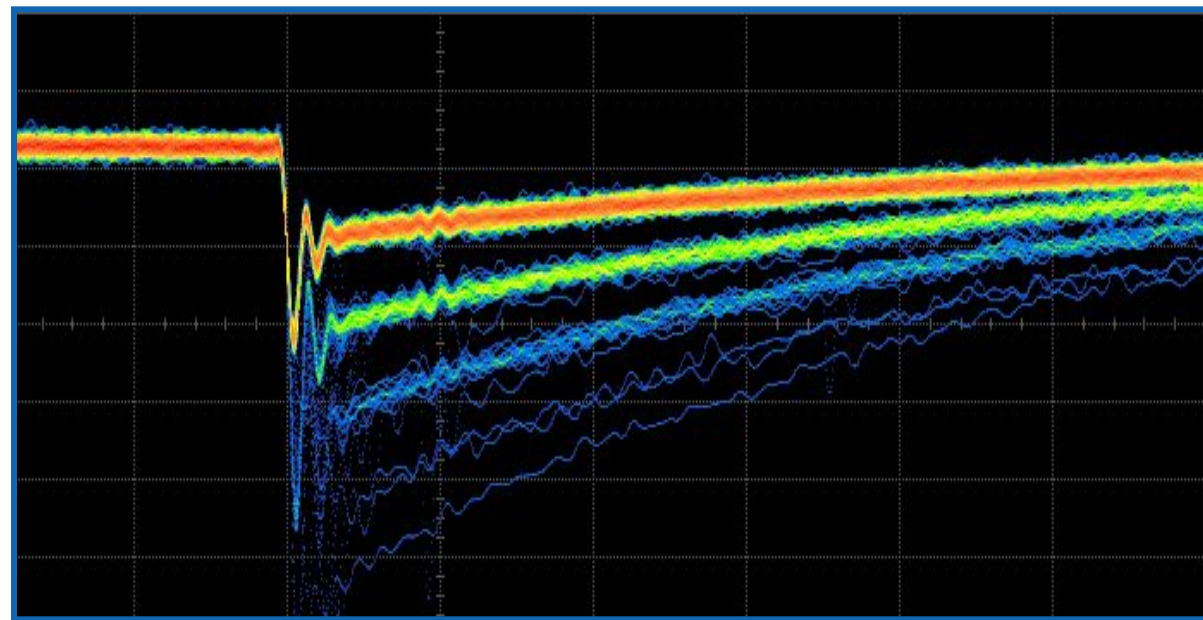
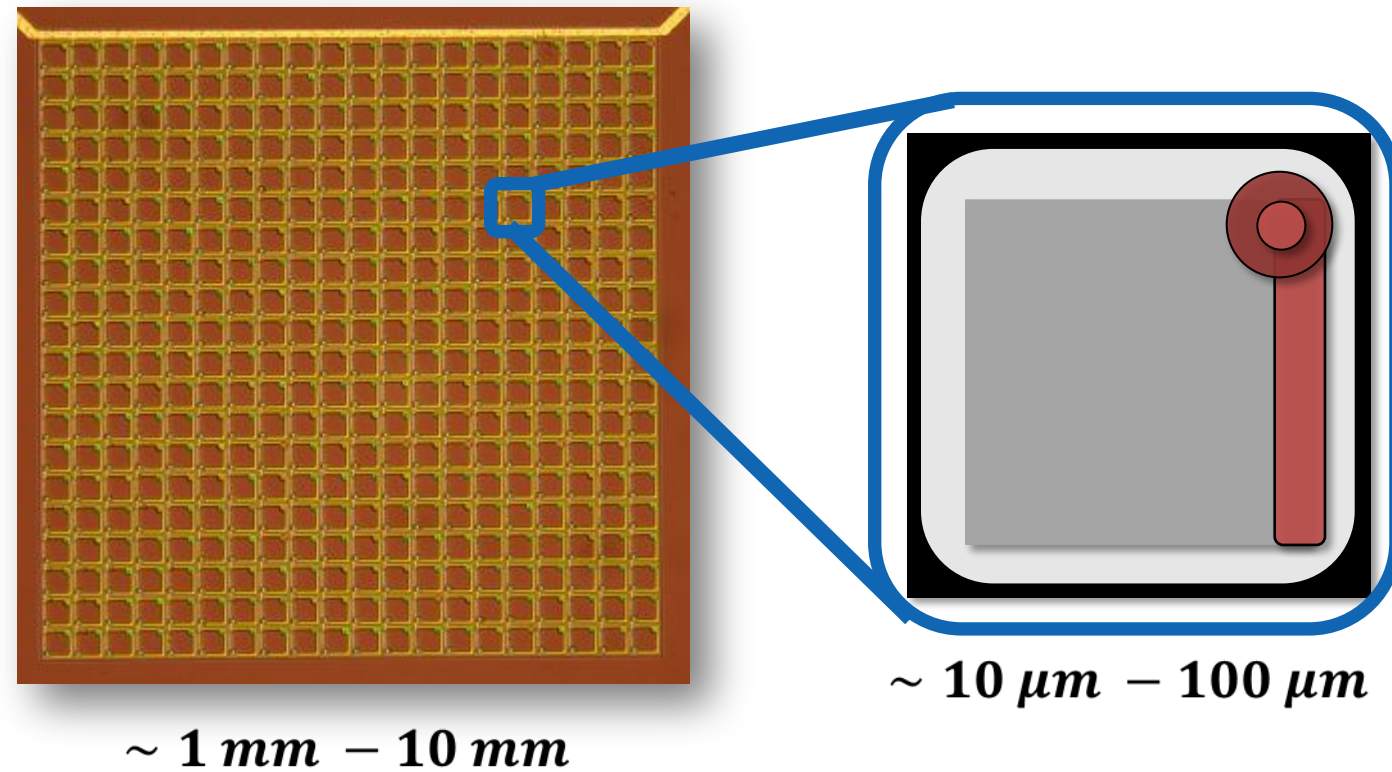
- Photon absorption or thermally generated carriers trigger the avalanche process → macroscopic current
- Avalanche quenched by an external circuit
 - Quenching resistor

Properties:

- High Gain ($G \sim 10^5 - 10^7$)
- Excellent timing (~ 20 ps FWHM)
- Low operating bias voltage (30 – 50 V)
- Single photon sensitivity

Introduction

Silicon PhotoMultiplier (SiPM)



SPADs connected in parallel and arranged in arrays

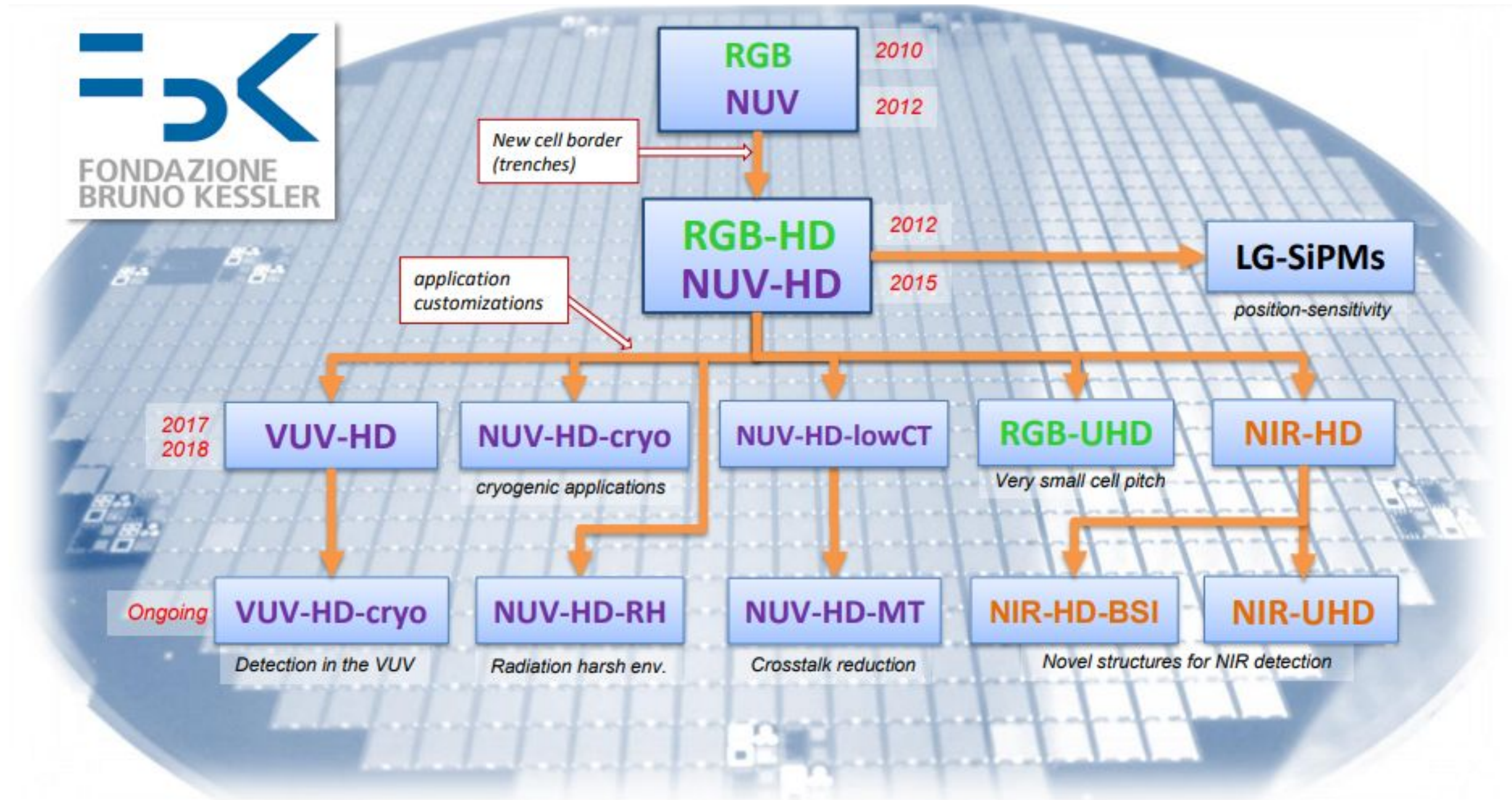
- $Q_{out} \propto N_{triggered\ cells} \propto N_{photons}$

Applications:

- Big Physics experiments
- Biomedical Imaging (PET, ToF-PET...)
- Industrial, automotive, ...

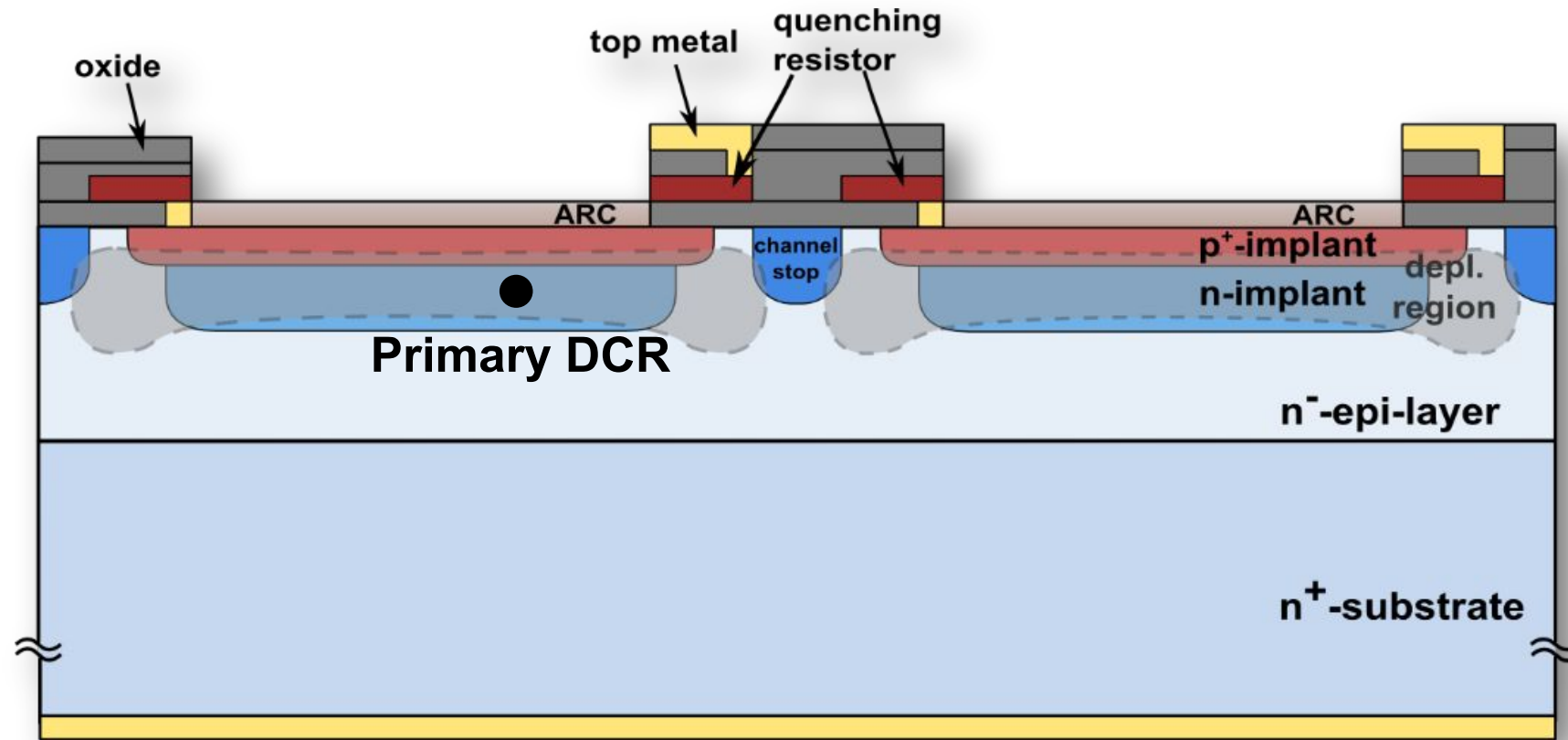
Introduction

FBK SiPM technologies



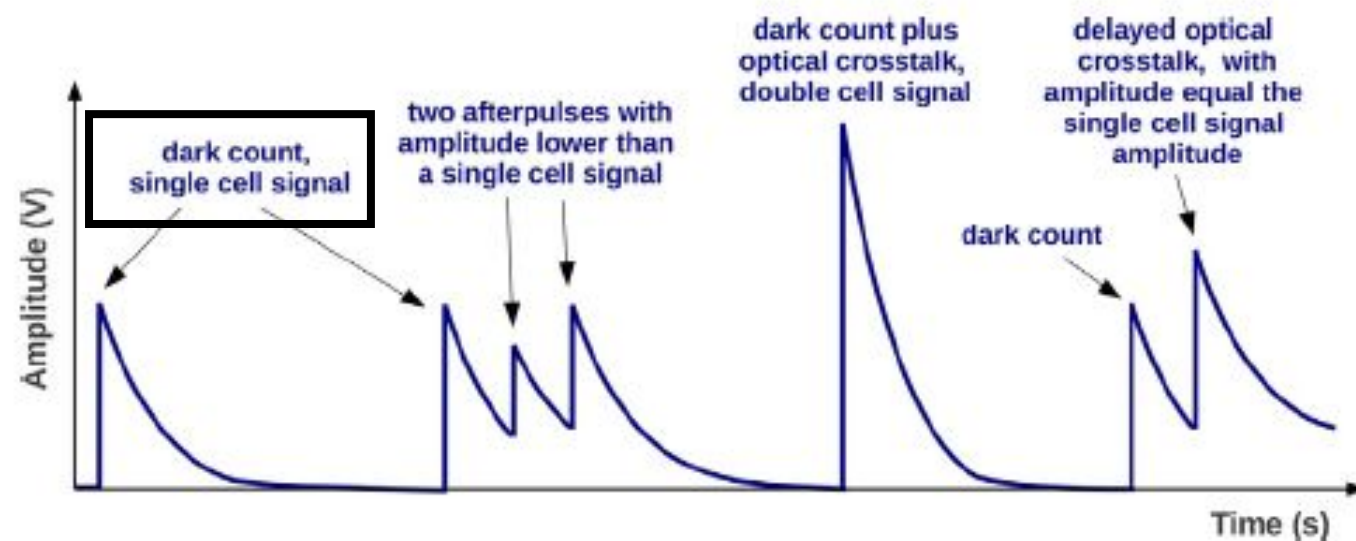
Introduction

Noise in SiPM



Primary Dark Count Rate

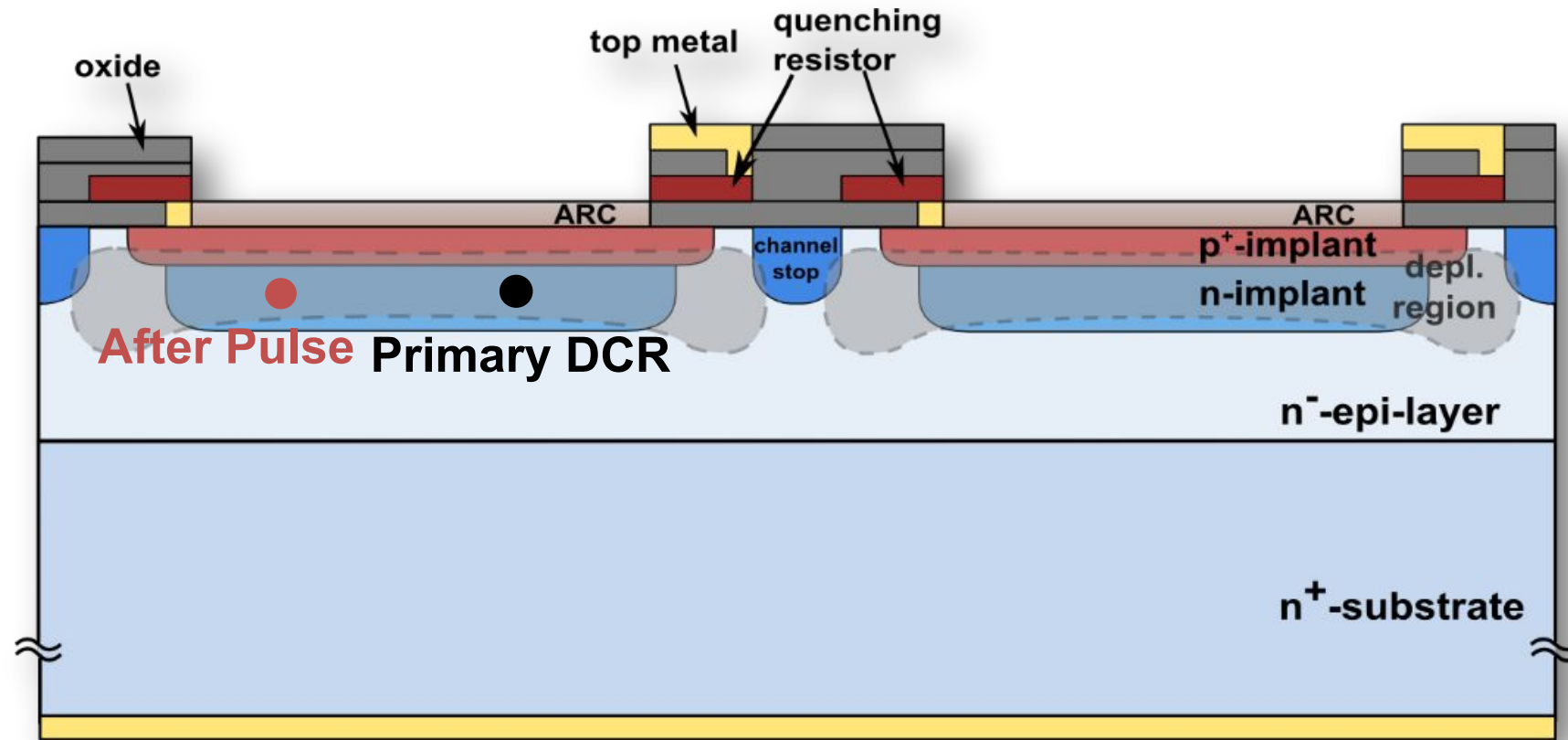
- Thermally generated carriers or tunneling



Acerbi F., Gundacker S., "Understanding and simulating SiPMs", Nuclear Instruments and Methods in Physics Research Section A, 926, 2019,16-35,, <https://doi.org/10.1016/j.nima.2018.11.118>.

Introduction

Noise in SiPM

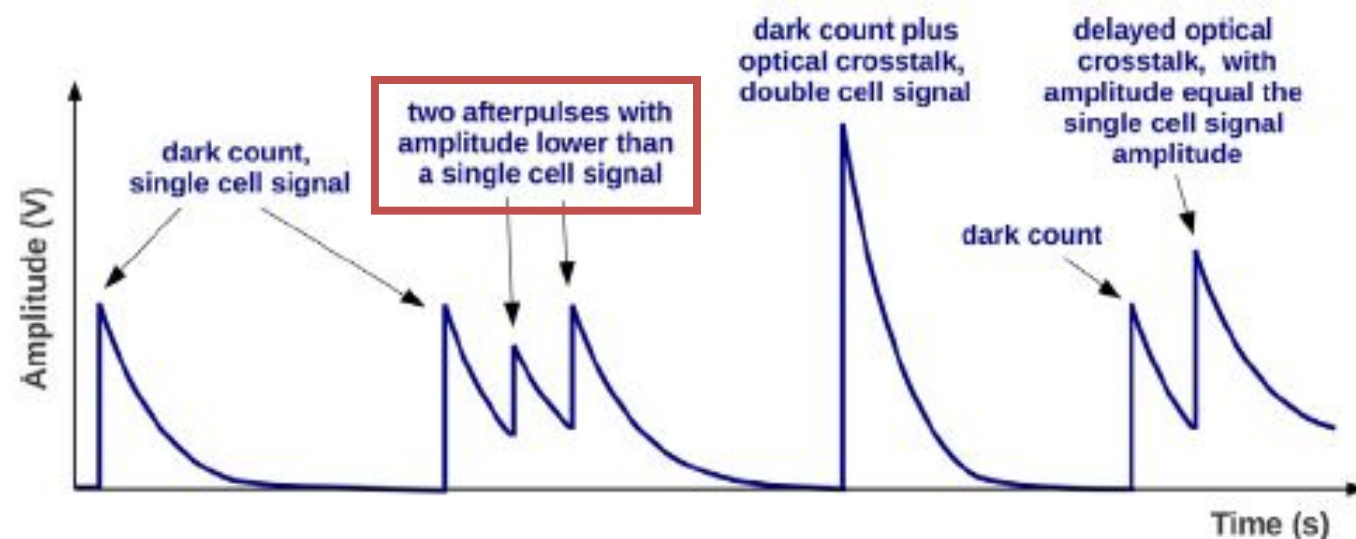


Primary Dark Count Rate

- Thermally generated carriers or tunneling

Afterpulsing

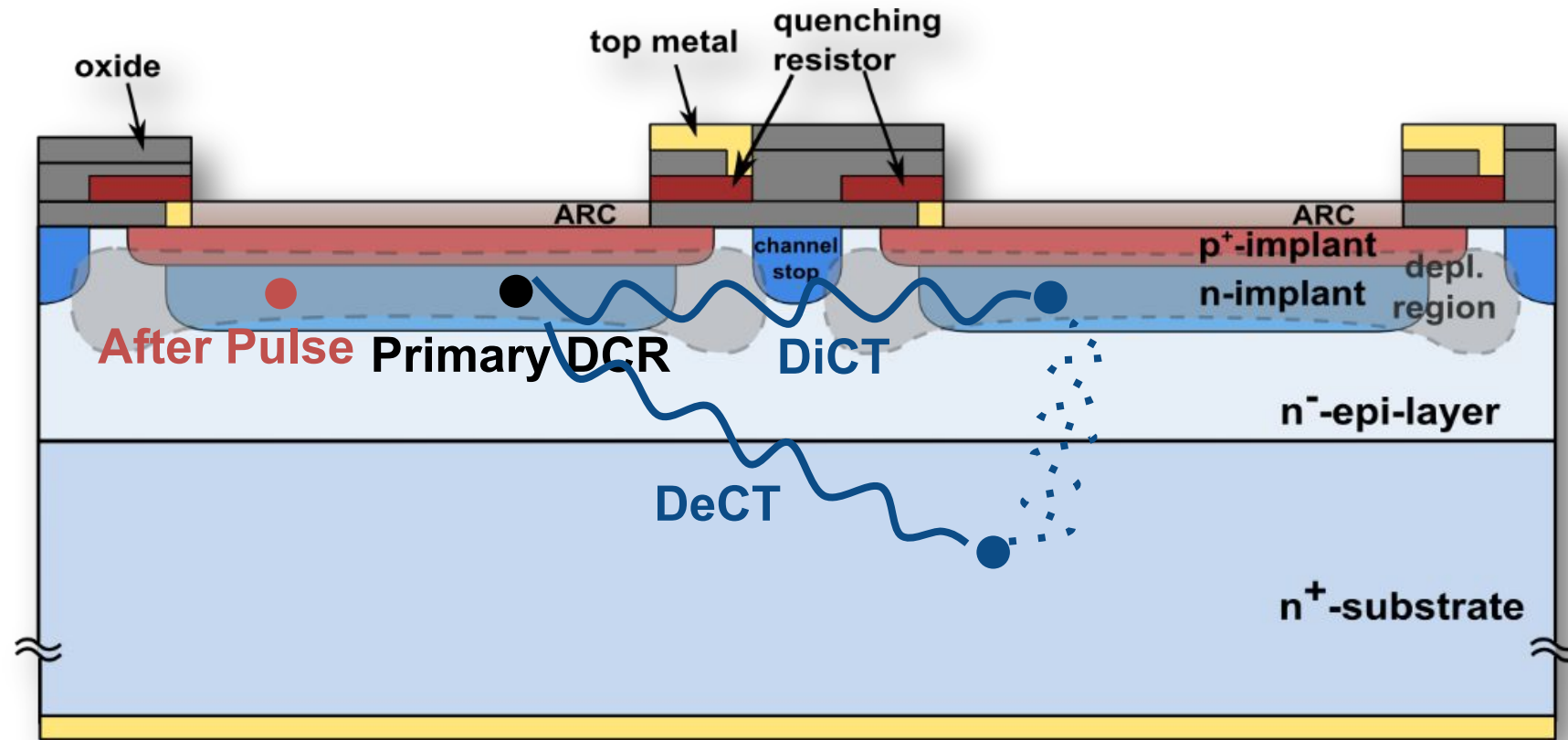
- Trapping and release of carriers in the same cell



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Introduction

Noise in SiPM



Primary Dark Count Rate

- Thermally generated carriers or tunneling

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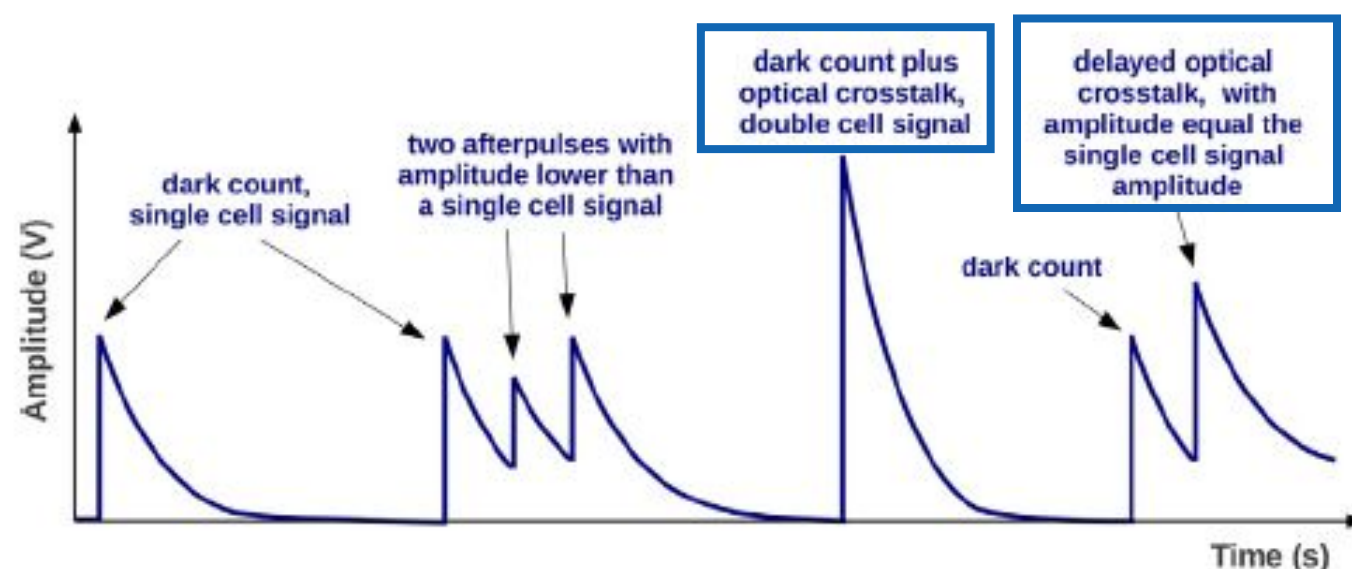
- Trapping and release of carriers in the same cell

Direct Cross Talk

- Secondary photons produced in the avalanche are absorbed in the neighboring cells

Delayed Crosstalk

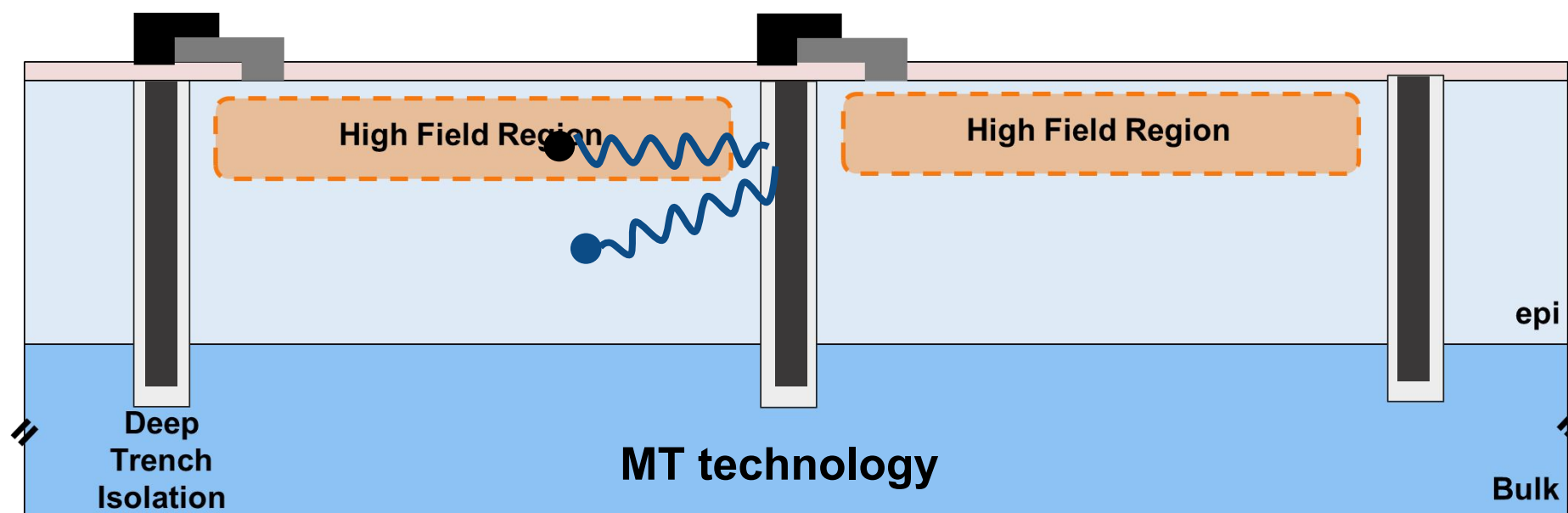
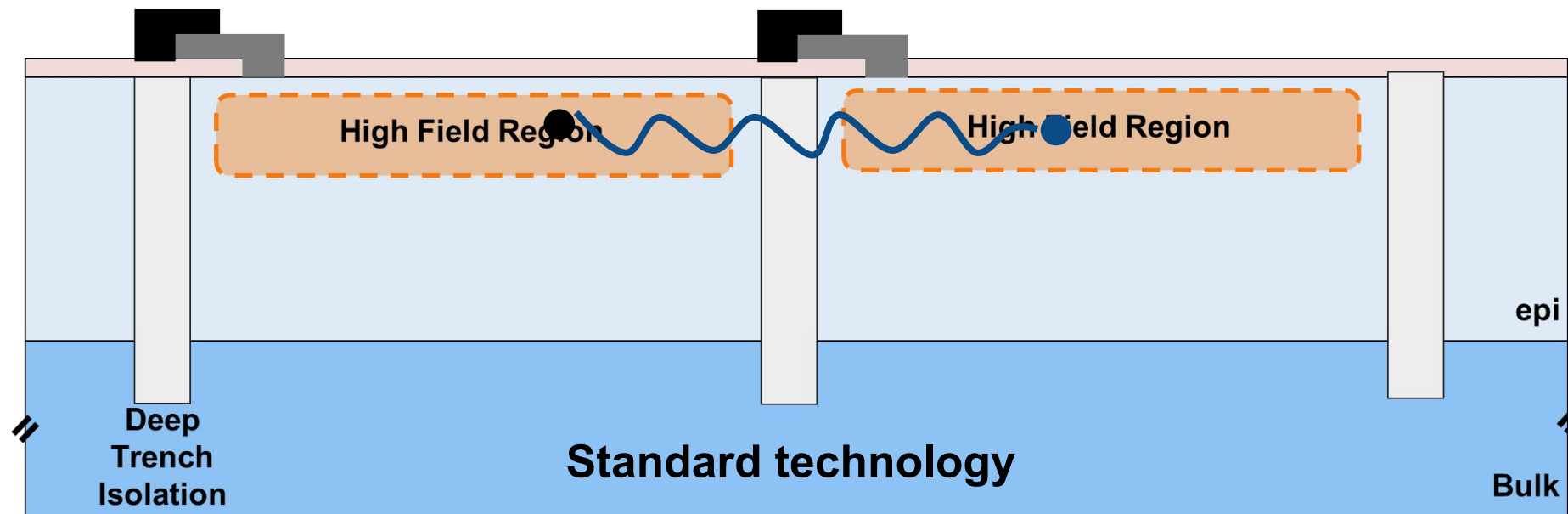
- Secondary photons produced in the avalanche are absorbed in the neutral region, then the photo-generated carriers diffuse towards the active region and trigger the avalanche in the neighboring cells



Acerbi F., Gundacker S., "Understanding and simulating SiPMs", Nuclear Instruments and Methods in Physics Research Section A, 926, 2019,16-35,, <https://doi.org/10.1016/j.nima.2018.11.118>.

Introduction

FBK NUV-HD SiPMs with metal-filled trenches (MT)



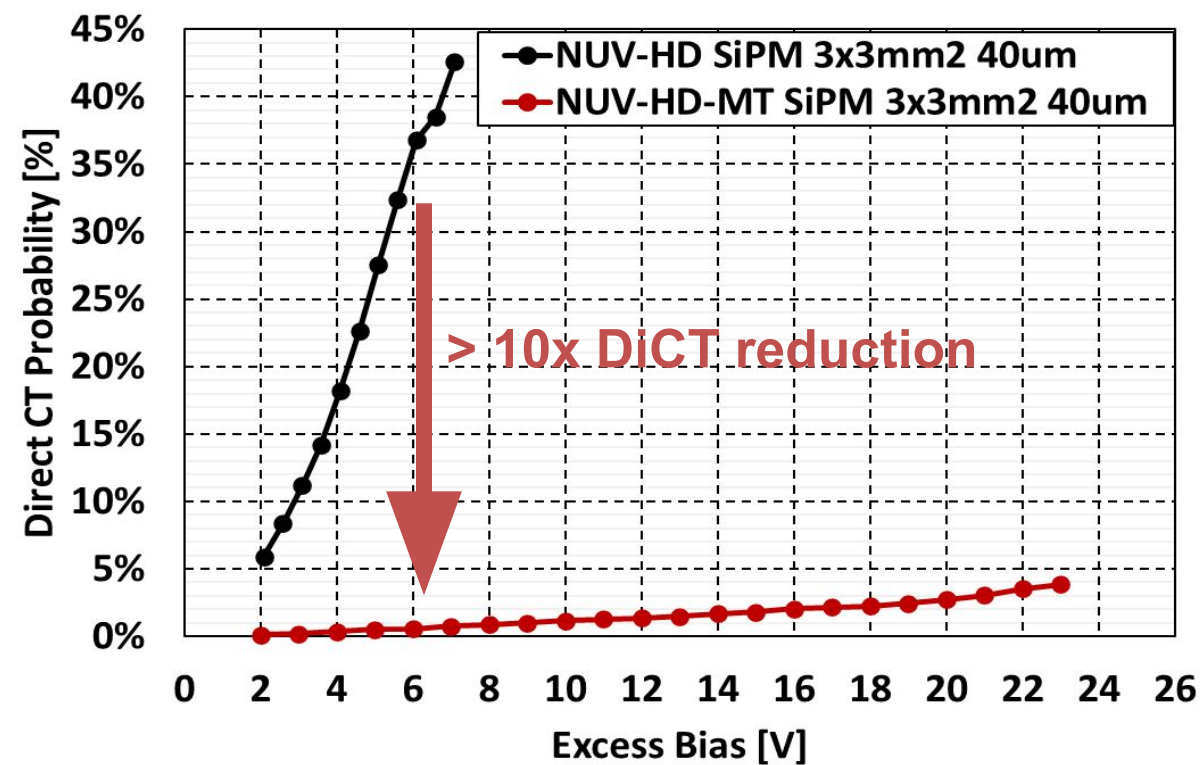
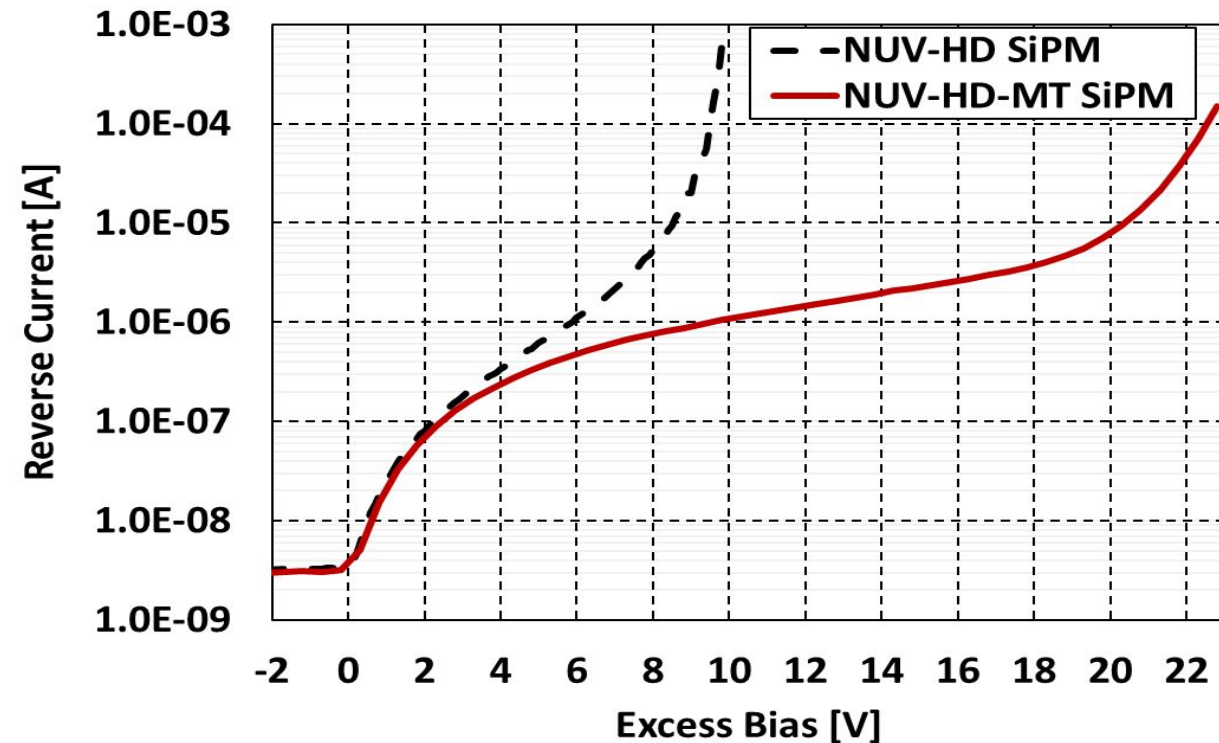
Collaboration with Broadcom

- Metal-filled trenches to optically isolate adjacent microcells

Stefano Merzi et al, "NUV-HD SiPMs with metal-filled trenches", 2023 JINST 18 P05040
DOI 10.1088/1748-0221/18/05/P05040

Introduction

FBK NUV-HD SiPMs with metal-filled trenches (MT)



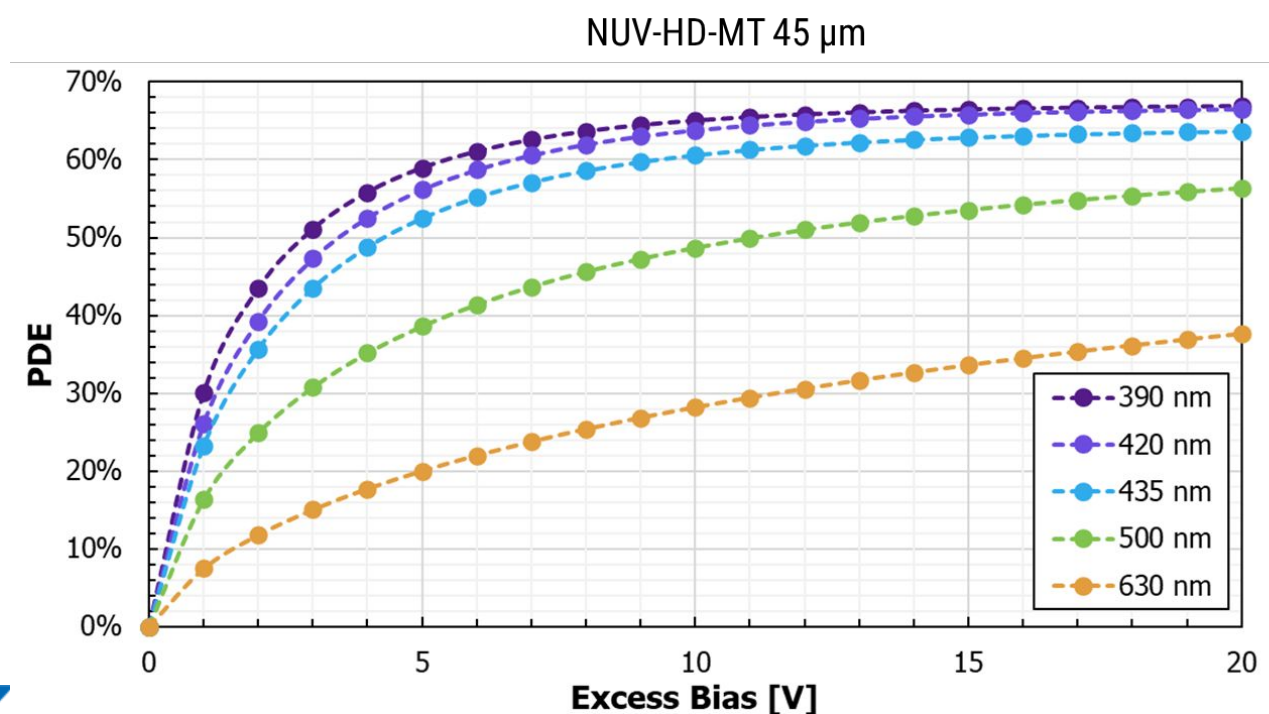
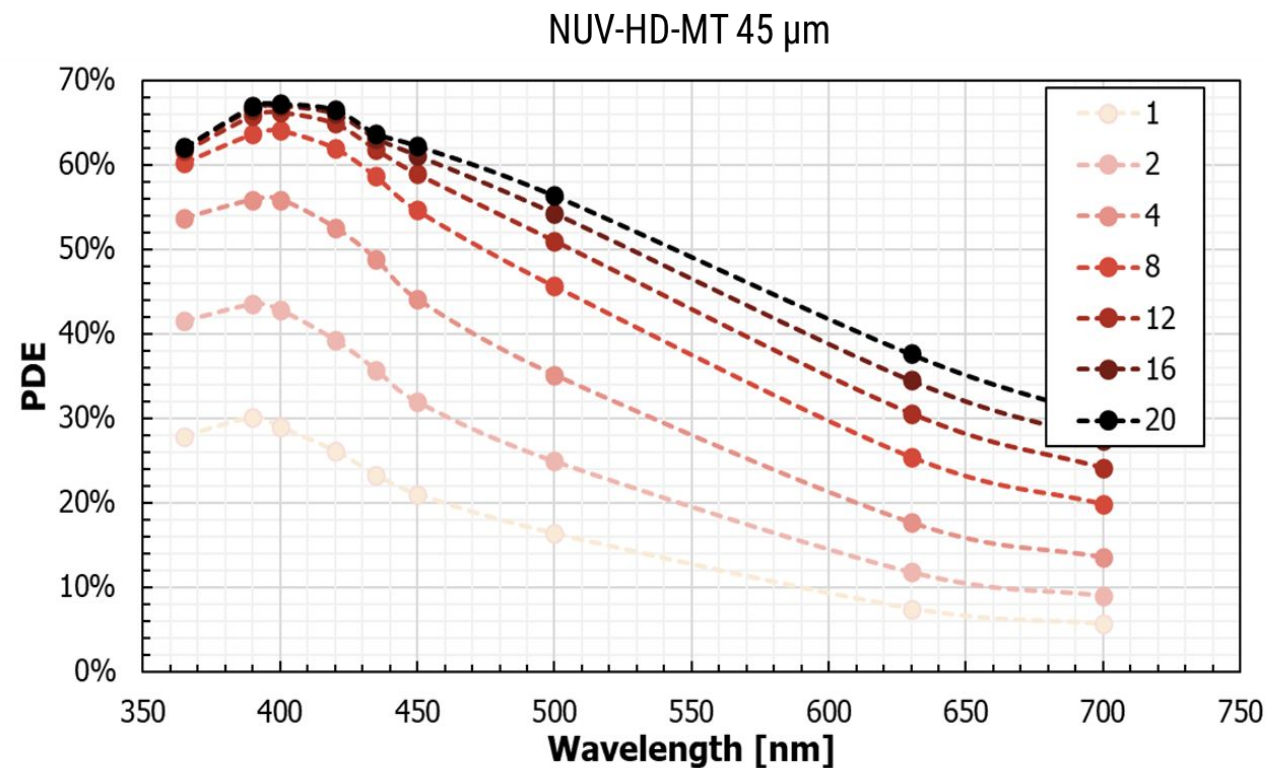
Collaboration with Broadcom

- Metal-filled trenches to optically isolate adjacent microcells
 - Significant reduction of the internal crosstalk
 - Significant increase of the operating voltage bias

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Introduction

FBK NUV-HD SiPMs with metal-filled trenches (MT)



Collaboration with Broadcom

- Metal-filled trenches to optically isolate adjacent microcells
 - Significant reduction of the internal crosstalk
 - Significant increase of the operating voltage bias
 - The extended bias range compensate the slight loss of Fill Factor (thus of PDE) due to the additional space used by the metal filling of the trenches
- PDE ~ 65%

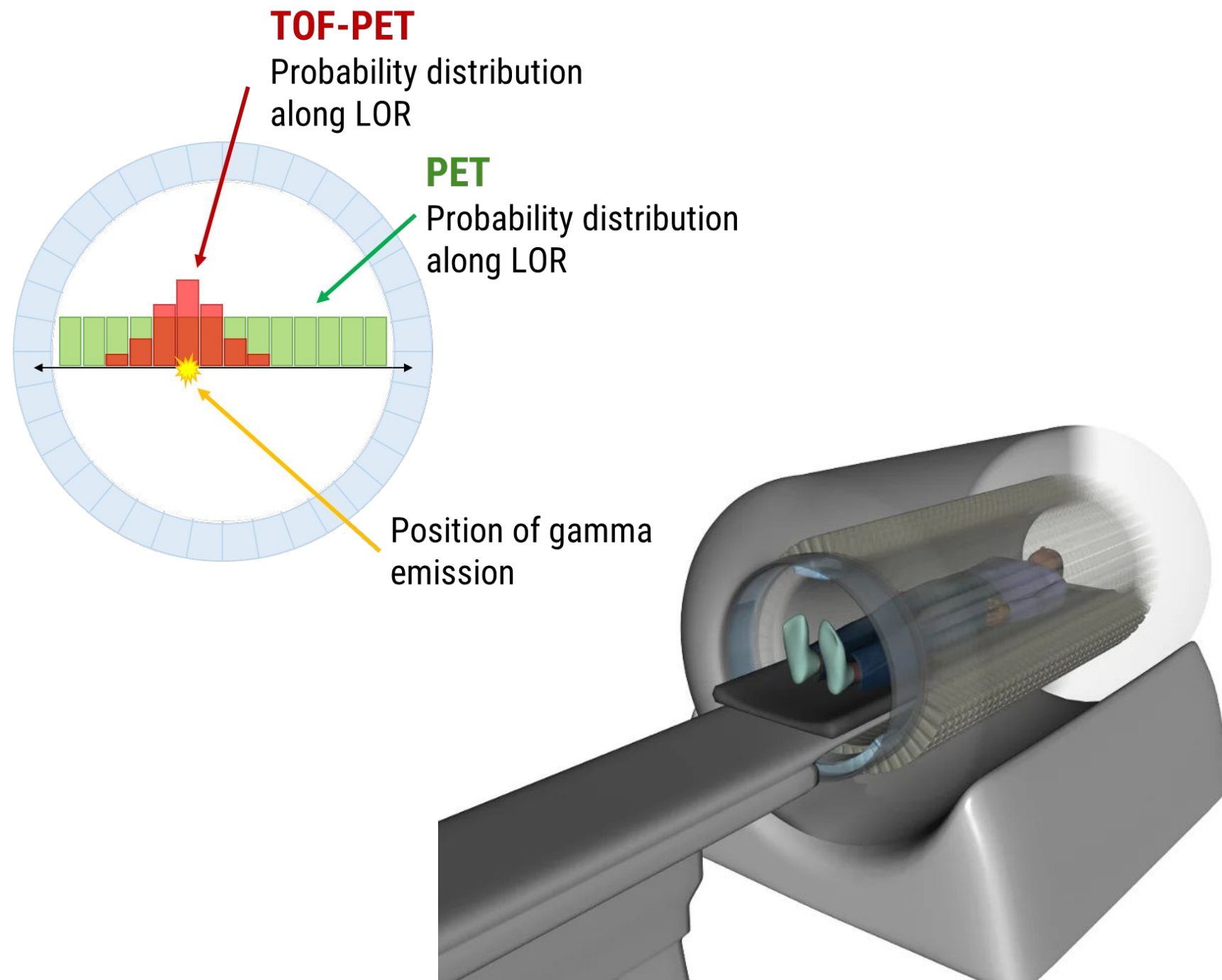
Stefano Merzi et al, "NUV-HD SiPMs with metal-filled trenches", 2023 JINST 18 P05040
 DOI 10.1088/1748-0221/18/05/P05040

Timing performances

Single Photon Time Resolution (SPTR)

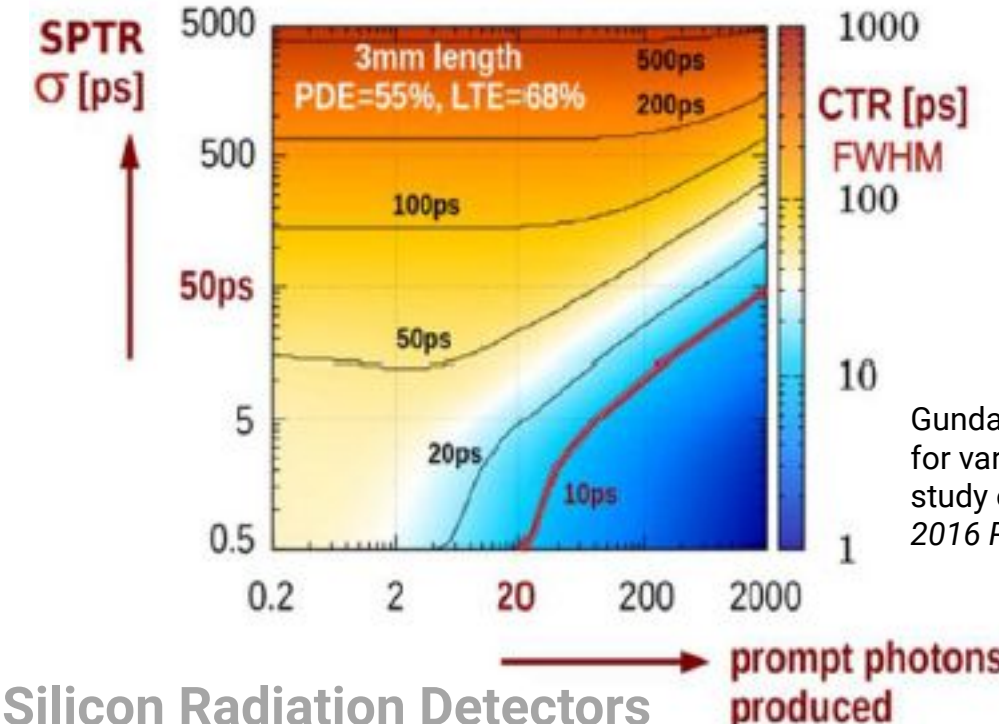
Single Photon Time Resolution

Timing performance applications



Time of Flight – Positron Emission Tomography (ToF-PET)

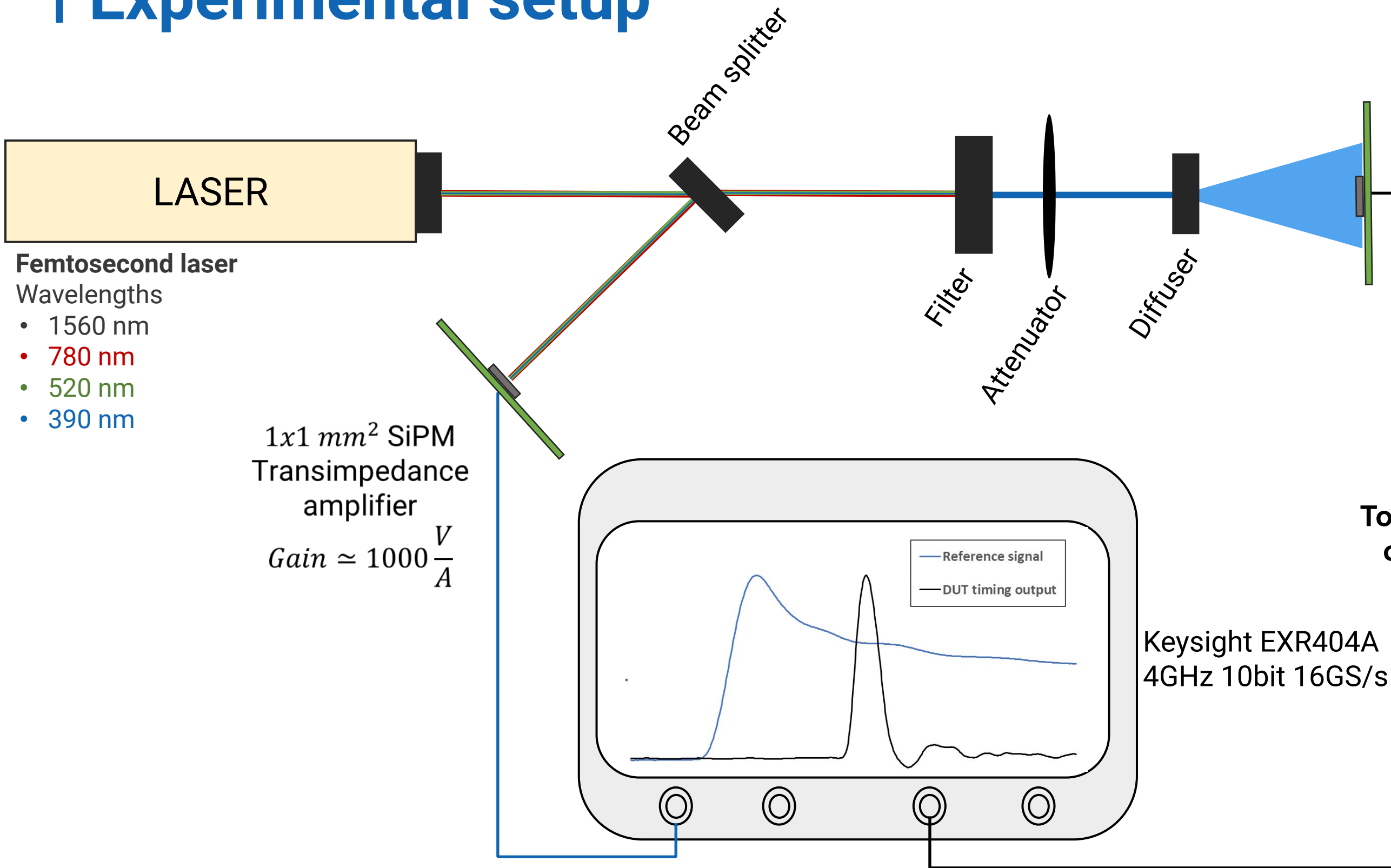
- Coincidence Time Resolution: good CTR → better reconstruction of the emission point along the Line Of Response (LOR)
- SPTR crucial for low light detection applications: timing with Cherenkov light



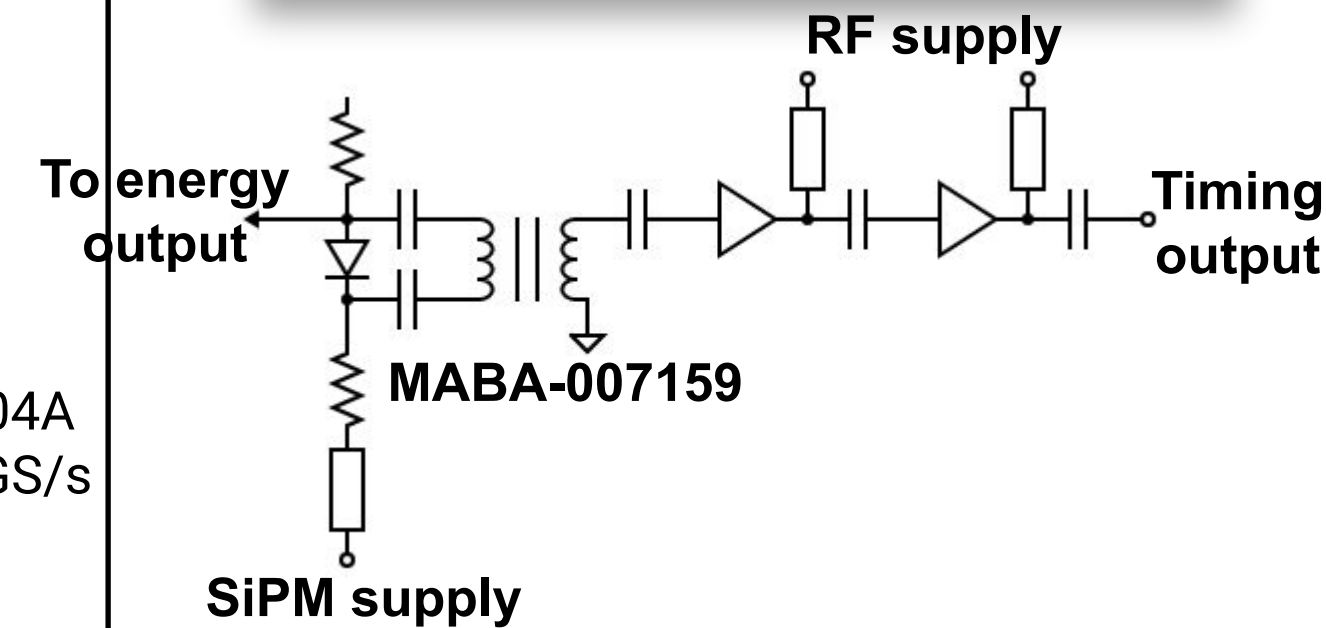
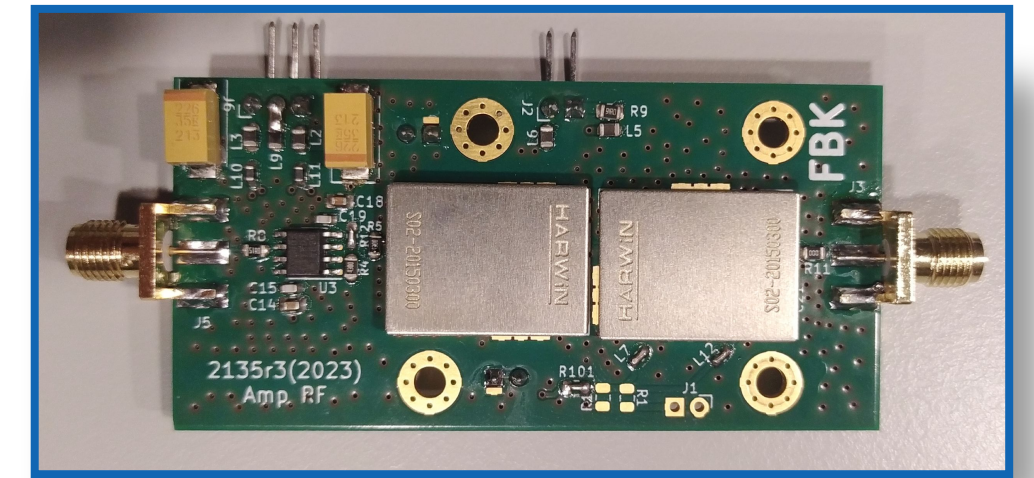
Cramér-Rao Lower Bound (CRLB) on coincidence time resolution for a 3 mm length LSO:Ce,Ca(0.4%) crystal.

Gundacker et al. "Measurement of intrinsic rise times for various L(Y)SO and LuAG scintillators with a general study of prompt photons to achieve 10 ps in TOF-PET." 2016 Phys. Med. Biol. 61 2802

Single Photon Time Resolution Experimental setup



HF readout developed at FBK
Implemented with BGA616



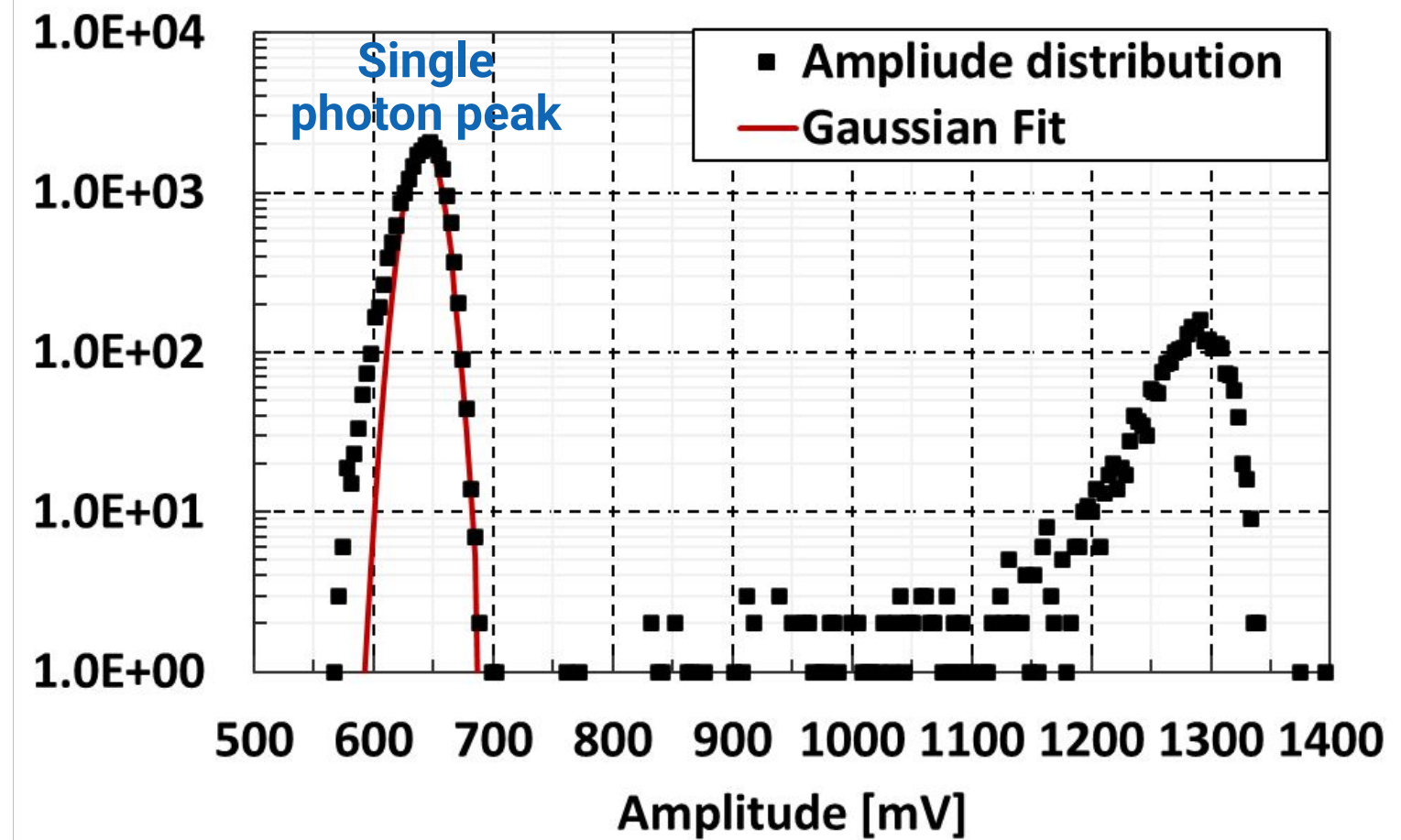
SPTR measurements have been performed with blue light (390nm)

Single Photon Time Resolution

Data acquisition and analysis

Amplitude distribution

- Gaussian fit on the single photon peak
 - $[\mu - 2\sigma, \mu + 2\sigma]$ taken as interval for the timing signals selection



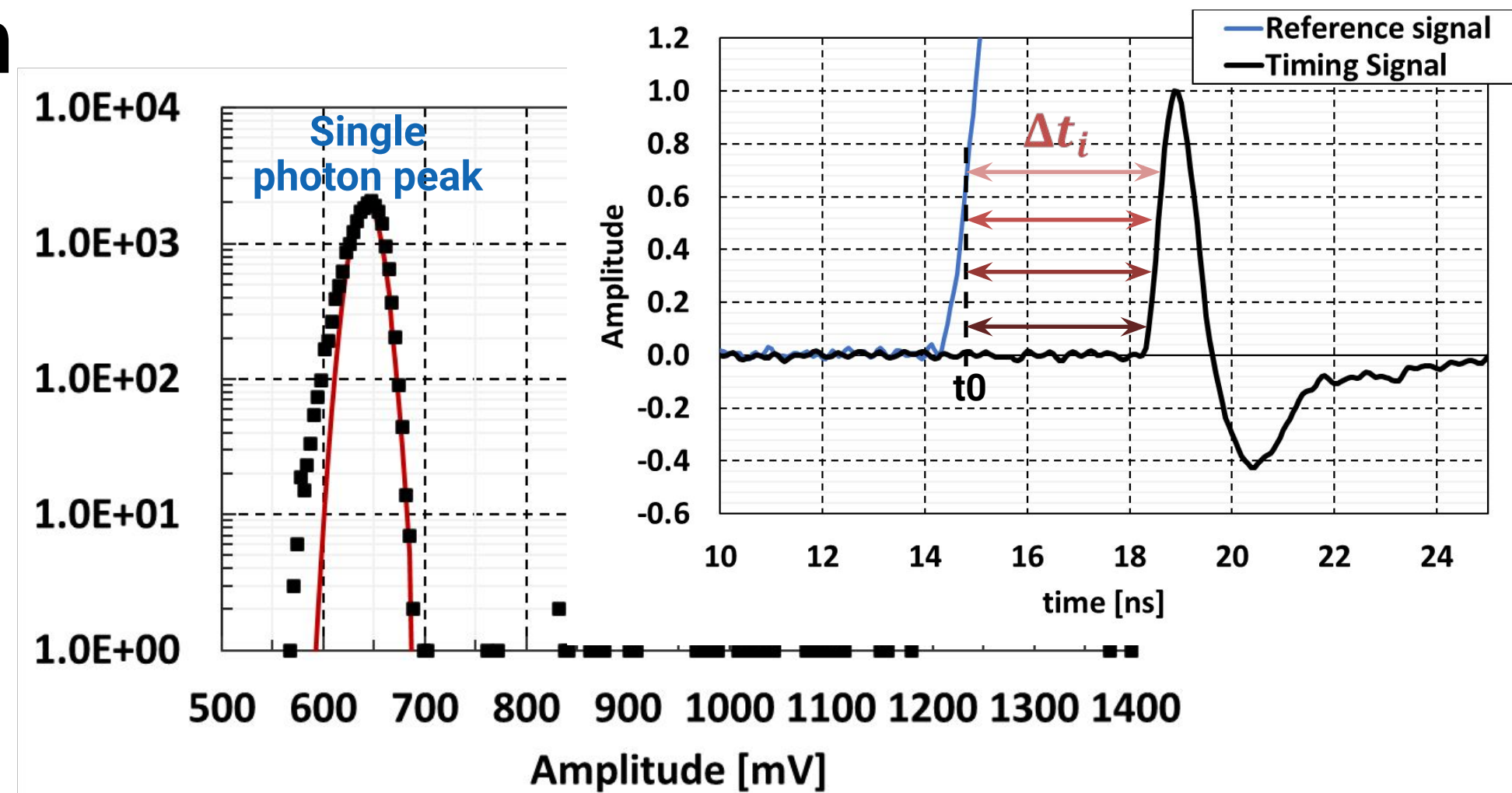
Single Photon Time Resolution Data acquisition and analysis

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Time delay distributions

- Time delays created from several threshold levels: scan along the leading edge (LED)
 - $\Delta t_i = t_i - t_0$: where t_0 is a single time stamp taken for the reference signal



Single Photon Time Resolution Data acquisition and analysis

Amplitude distribution

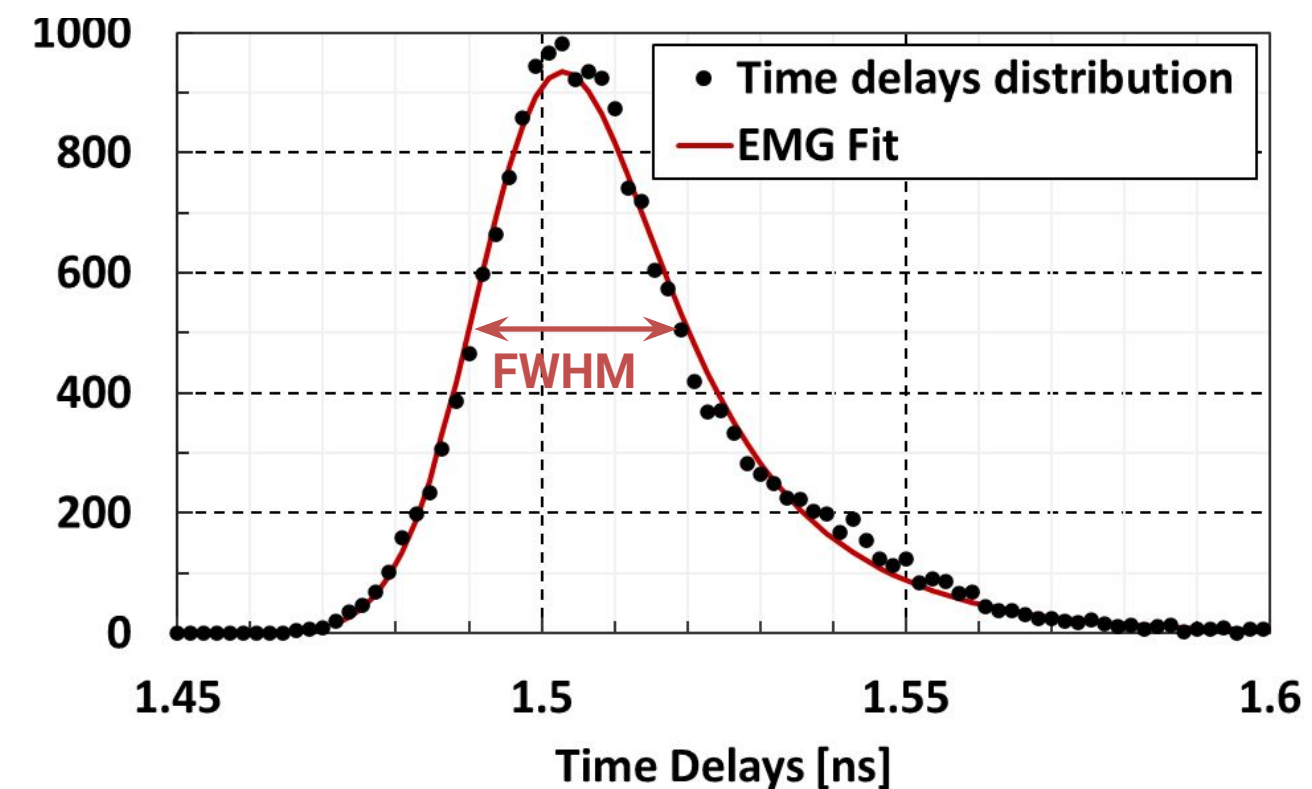
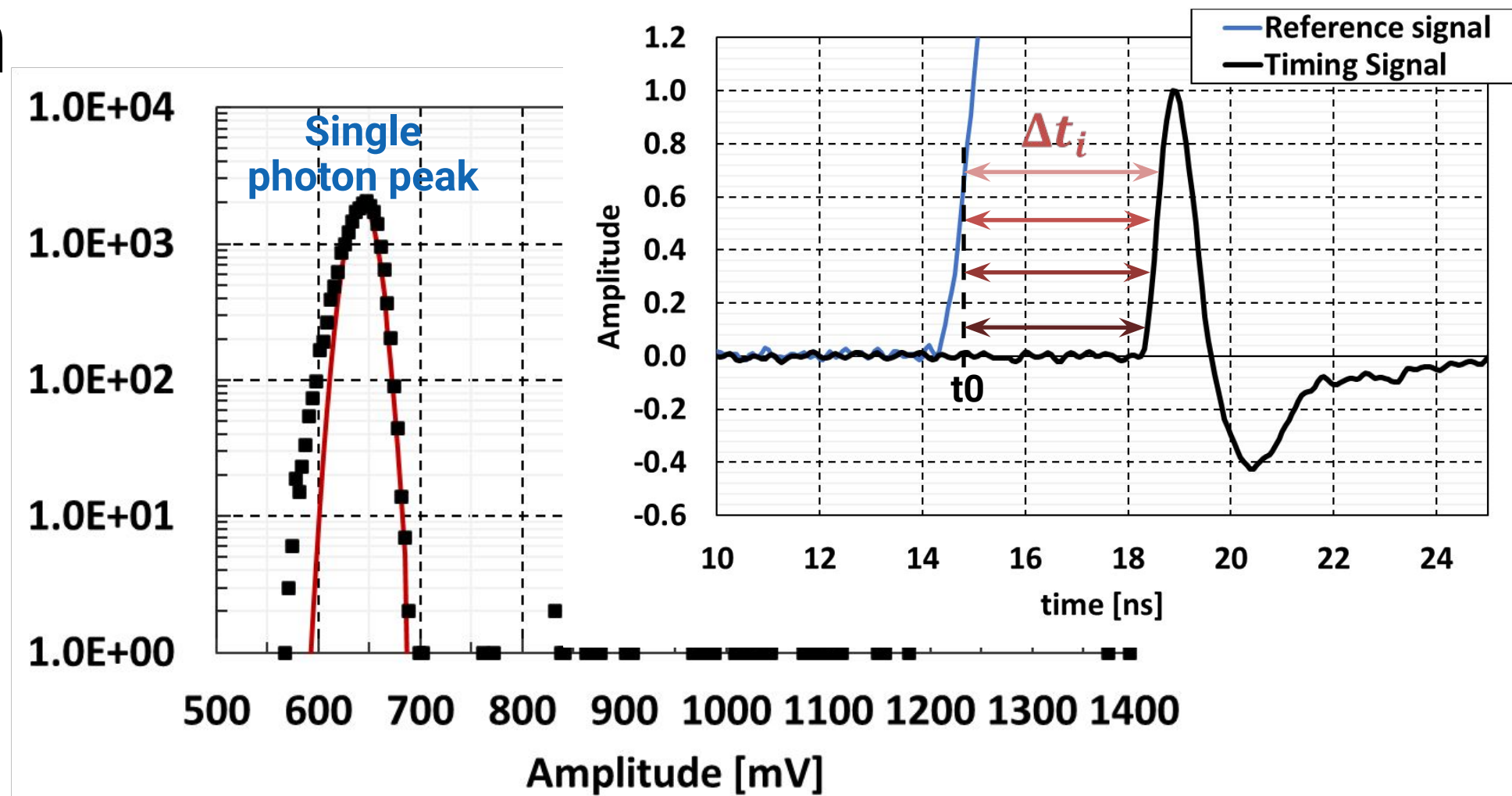
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Time delay distributions

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FWHM vs thresholds

- Each time delay distribution is fitted with an Exponential Modified Gaussian
- The FWHM is taken as SPTR

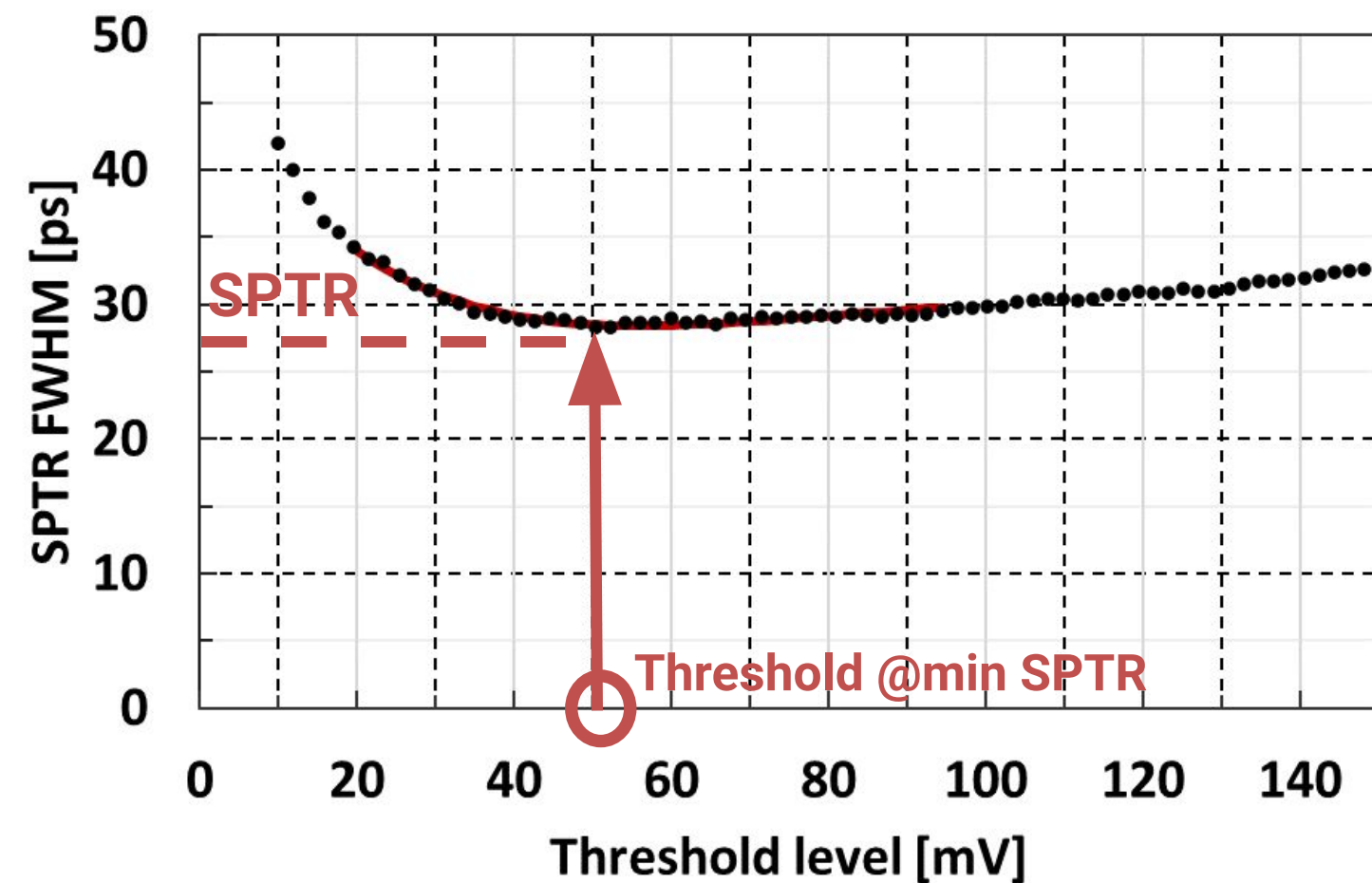


Single Photon Time Resolution

Data selection and methodologies

FWHM vs threshold plot

- Fitted with a polynomial
 - The minimum of the fit is the SPTR measurement
 - The threshold corresponding at the SPTR is the threshold used for the electronic noise jitter contribution



Single Photon Time Resolution

Devices tested

SPAD cell sizes

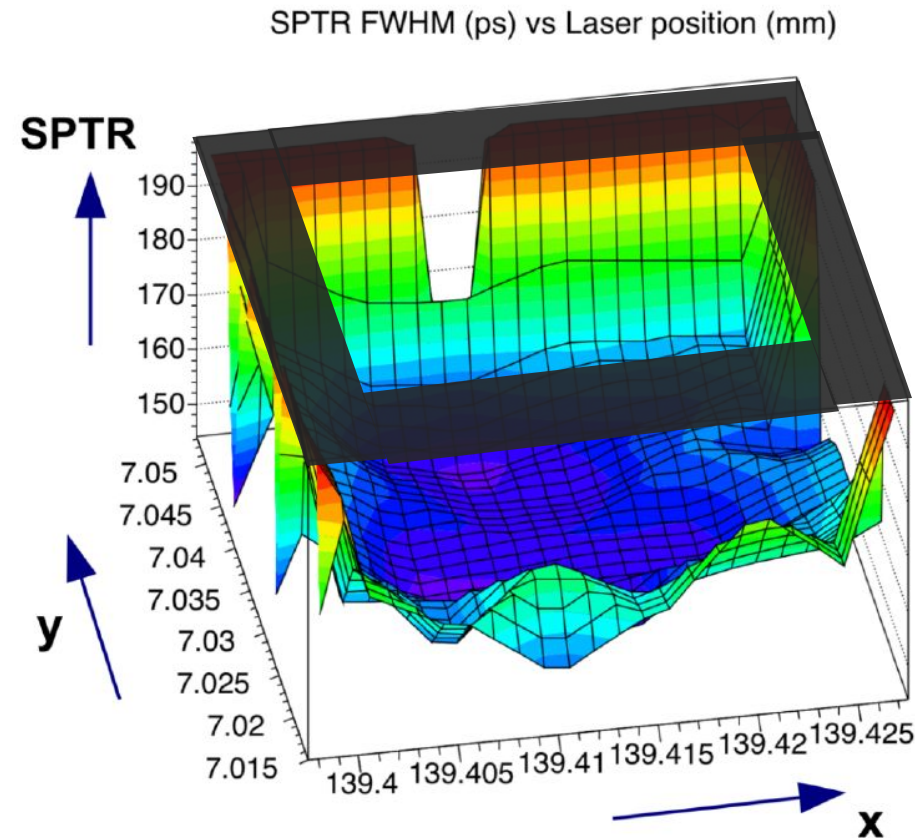
- 30 μm , 40 μm , 50 μm

SiPM dimensions

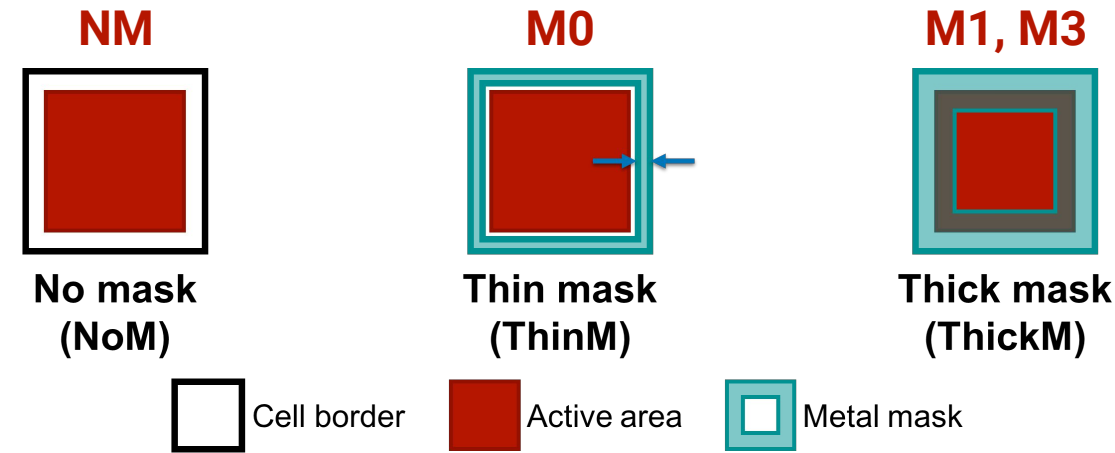
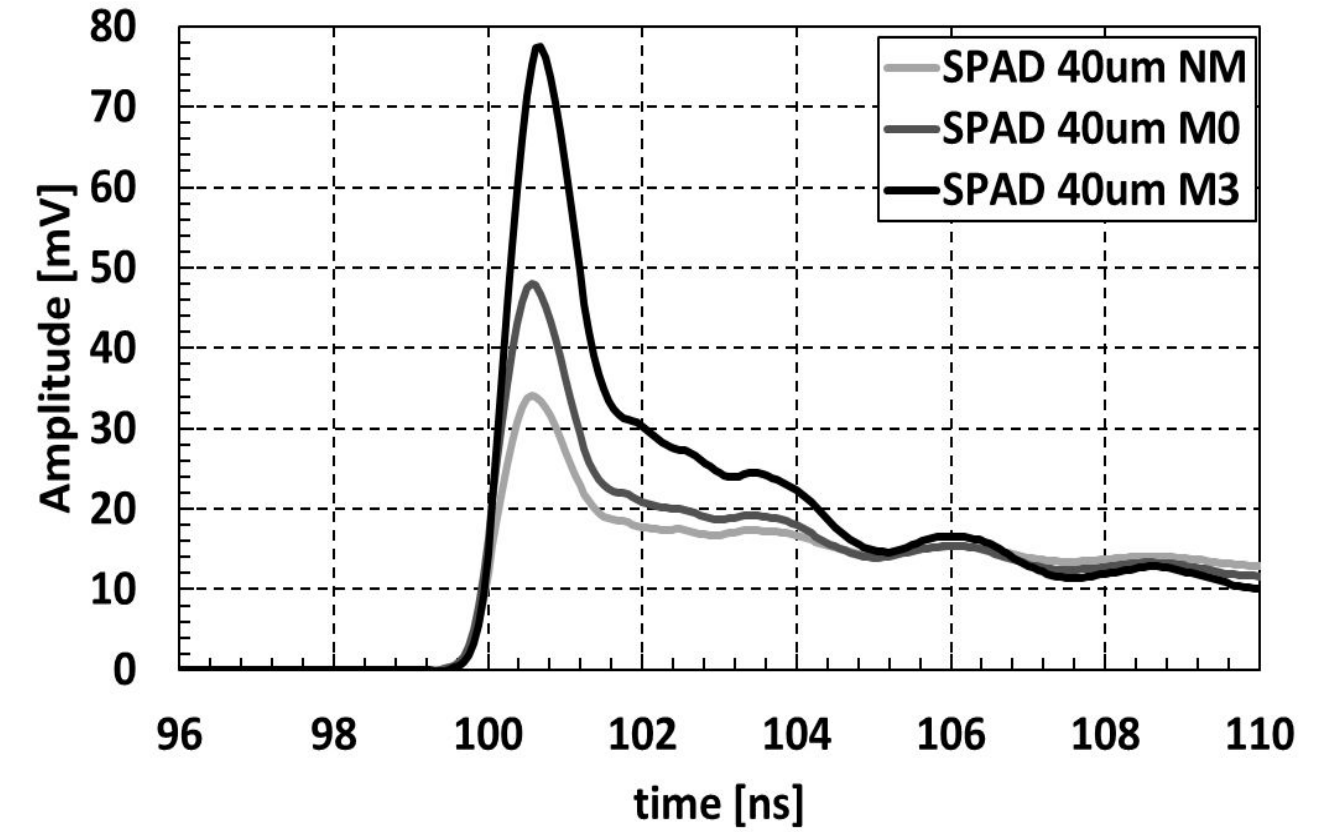
- Cell size: 40 μm
- 1x1 mm^2 , 3x3 mm^2 , 4x4 mm^2

Mask versions

- Masked: 0 μm , 3 μm overlap with the active area
 - Remove the outer areas of the SPAD which show worse SPTR
 - A higher capacitive coupling between anode and readout: increase the fast peak of the single cell response

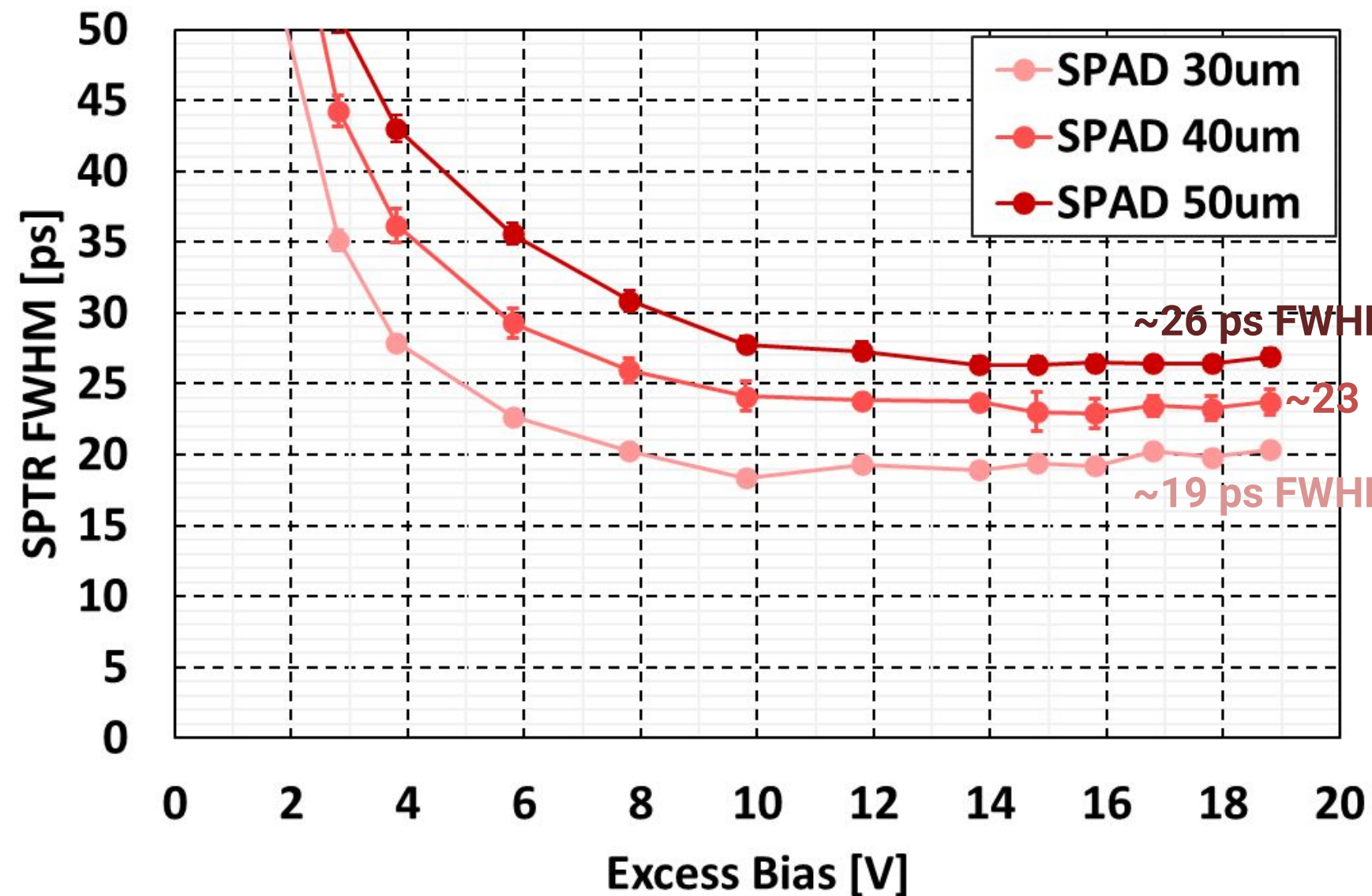


Nemallapudi, M. V., et al. "Single photon time resolution of state-of-the-art SiPMs." *Journal of Instrumentation* 11.10 (2016): P10016.



Stefan Gundacker et al, " On timing-optimized SiPMs for Cherenkov detection to boost low cost time-of-flight PET", 2023 Phys. Med. Biol. 68 165016

Single Photon Time Resolution (SPTR) Results



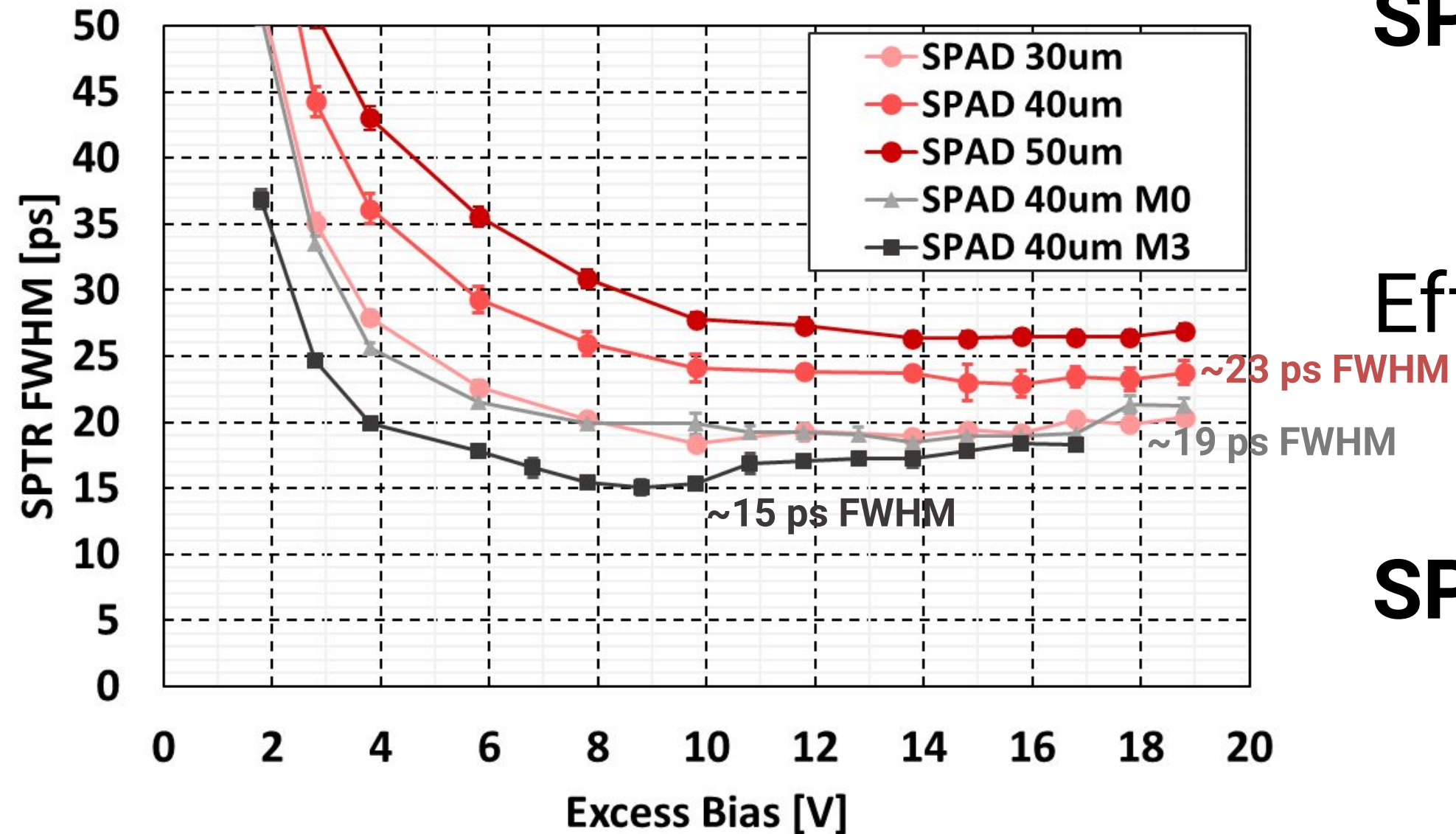
SPTR vs microcell size

- The SPTR get worse with the cell size

Effect under investigation

- Maybe related to the position where the avalanche starts

Single Photon Time Resolution (SPTR) Results



SPTR vs microcell size

- The SPTR get worse with the cell size

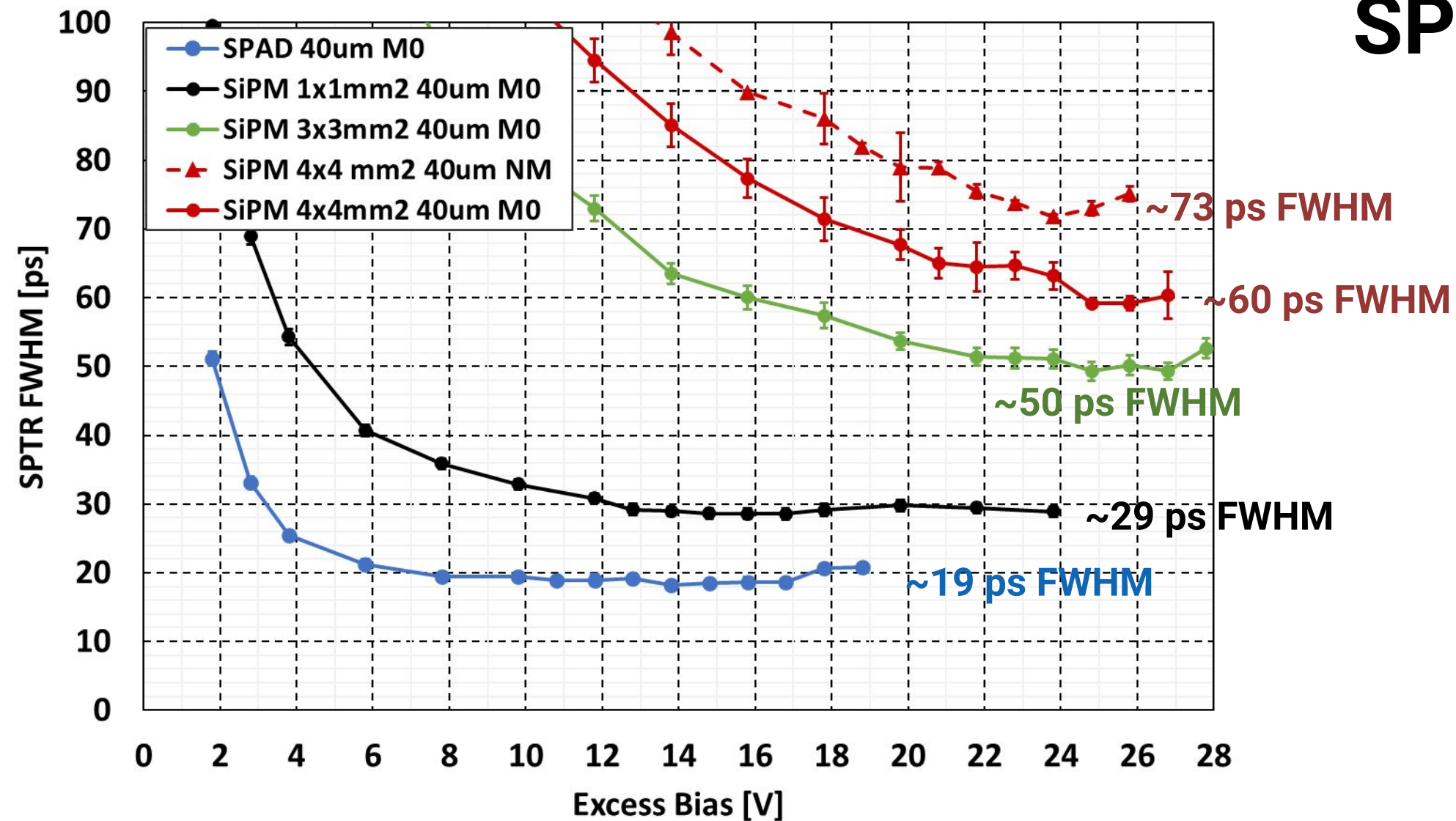
Effect under investigation

- Maybe related to the position where the avalanche starts

SPTR vs mask version

- Strong improvement of the SPTR related to the mask implementation

Single Photon Time Resolution (SPTR) Results

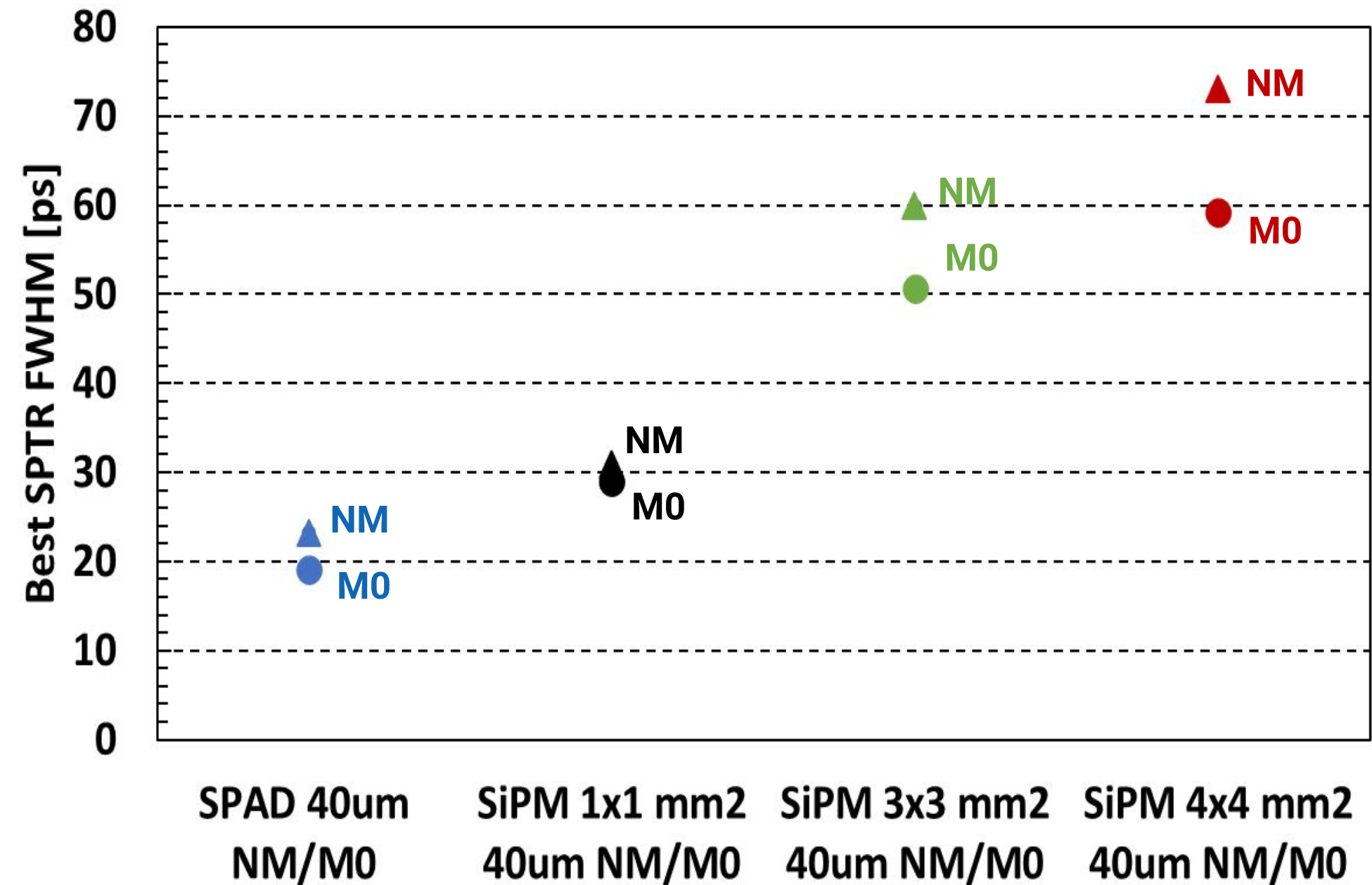
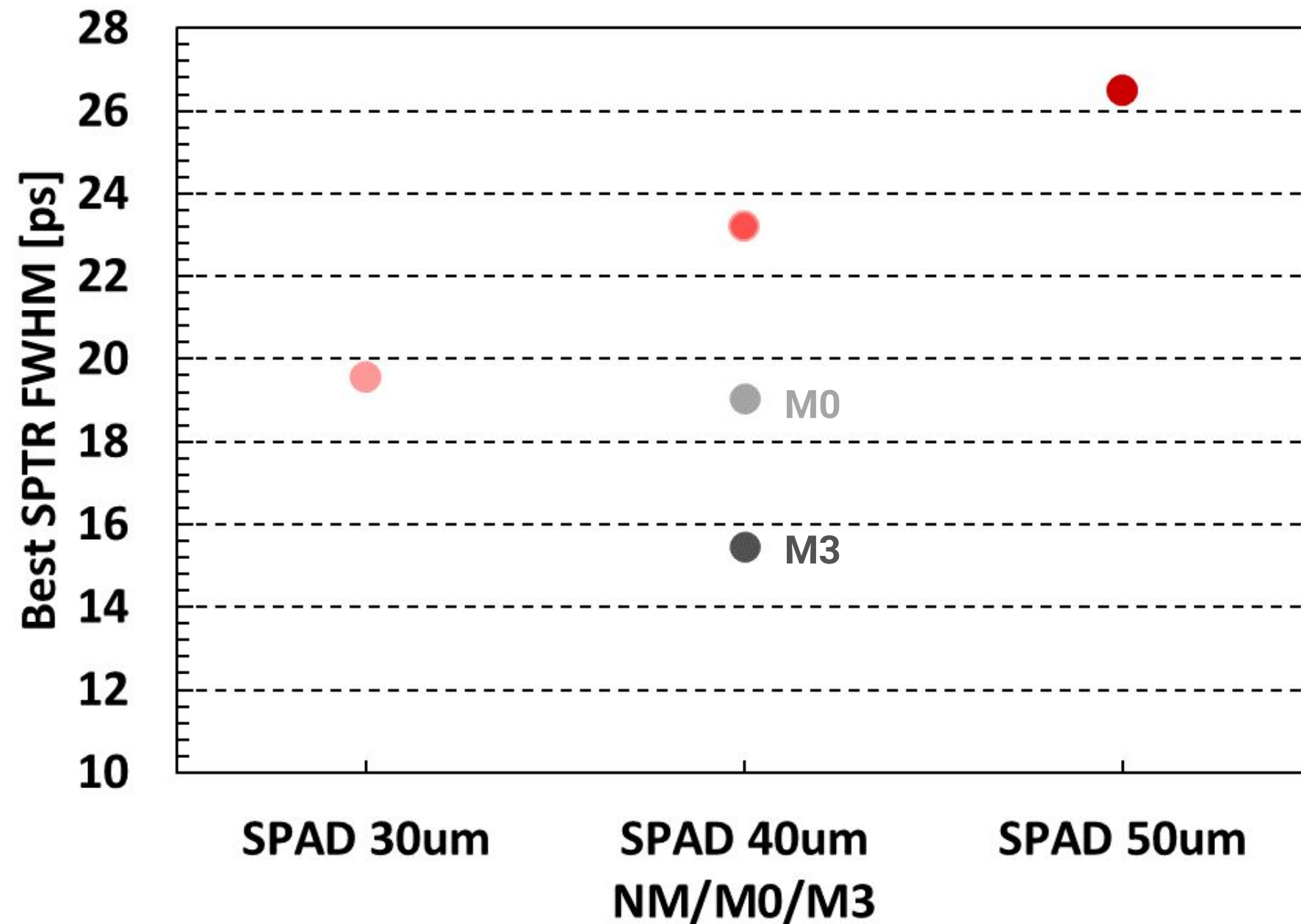


SPTR vs SiPM dimension

- SPTR get worse for bigger SiPMs
 - Self-filtering effect
 - Transit Time Spread
- Importance of the device segmentation

Single Photon Time Resolution (SPTR)

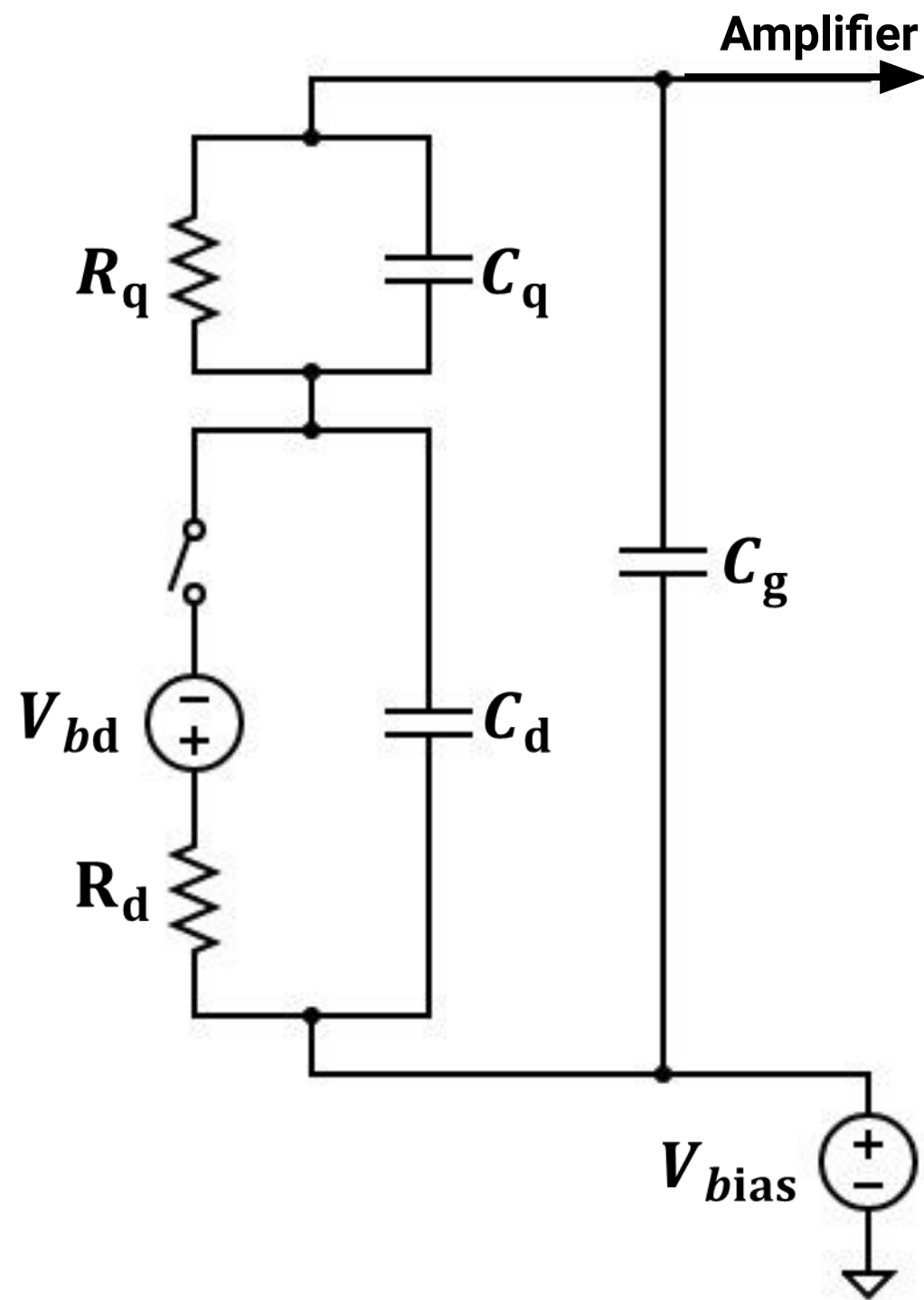
SPTR results summary



SPAD signal electrical simulations

SPAD equivalent electrical circuit

SPAD equivalent electrical circuit



Crucial to have a reliable model to

- Tune the design process (e.g. optimize the sensor)
- Front-end design
- Match the experiment constraints

Electrical parameters

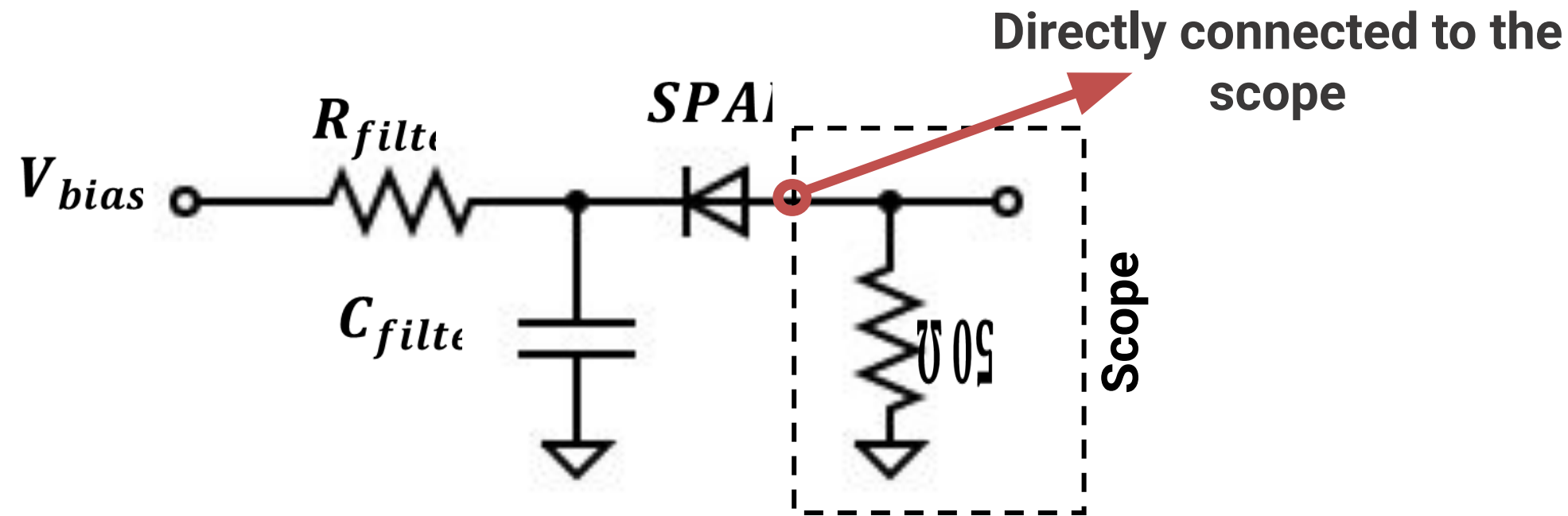
- R_d diode resistance
- C_d diode capacitance
- R_q quenching resistance
- C_q quenching capacitance
- C_g grid capacitance

SPAD signal electrical simulations

Electrical parameters extraction

Electrical parameters extraction

Quenching and diode capacitance



Device Under Test

- NUV-HD-MT SPAD 50um

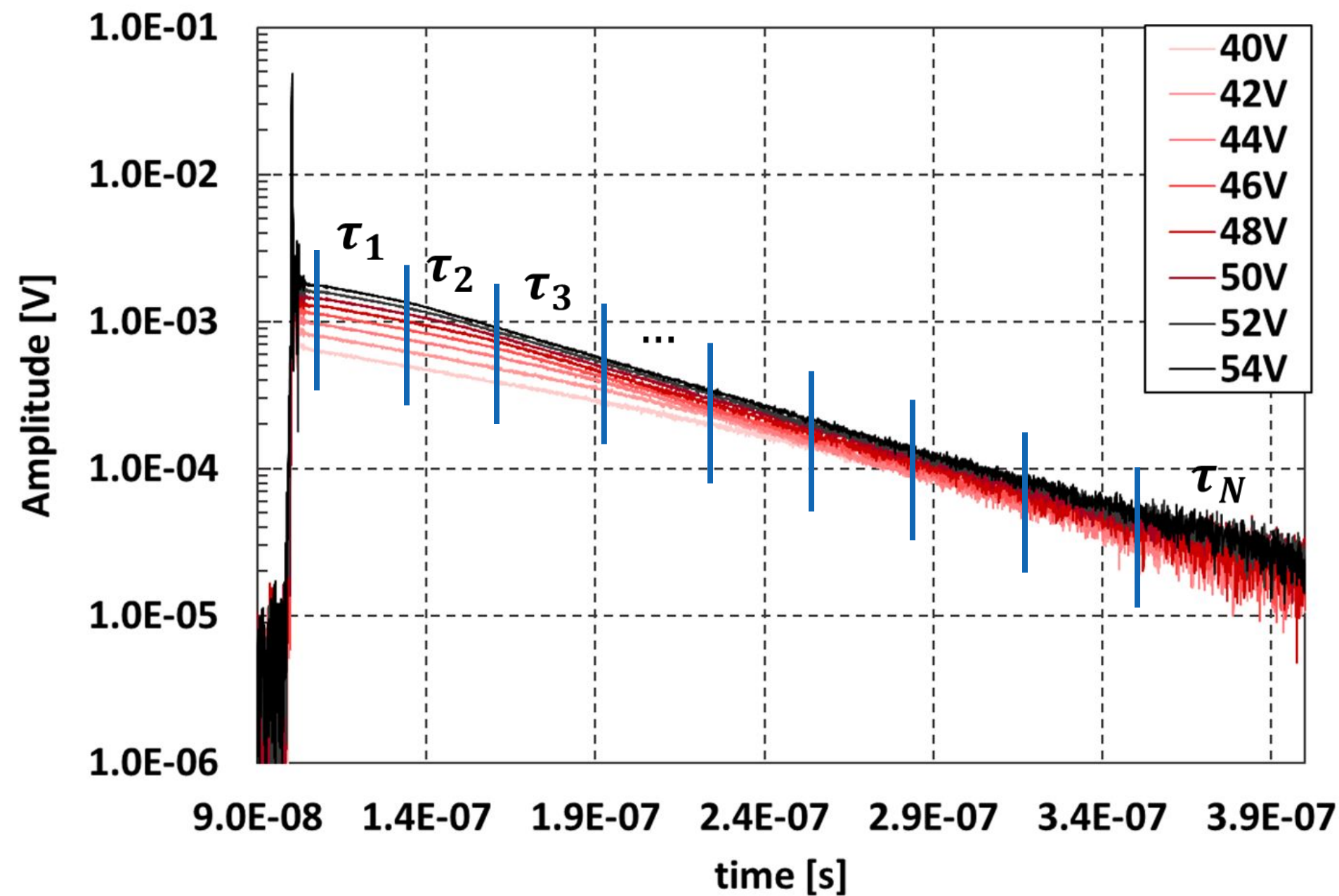
Oscilloscope

- Sampling rate: 16Gs/s
- 62.5ps/pt
- NO interpolation
- Bandwidth: 4GHz
- Z_{in} scope: 50 Ω



Electrical parameters extraction

Voltage varying capacitance model



- By assuming that for small time intervals (small variation of the voltage across C_d), C_d is constant...
 - ...you can fit the recharge of the signal in several intervals

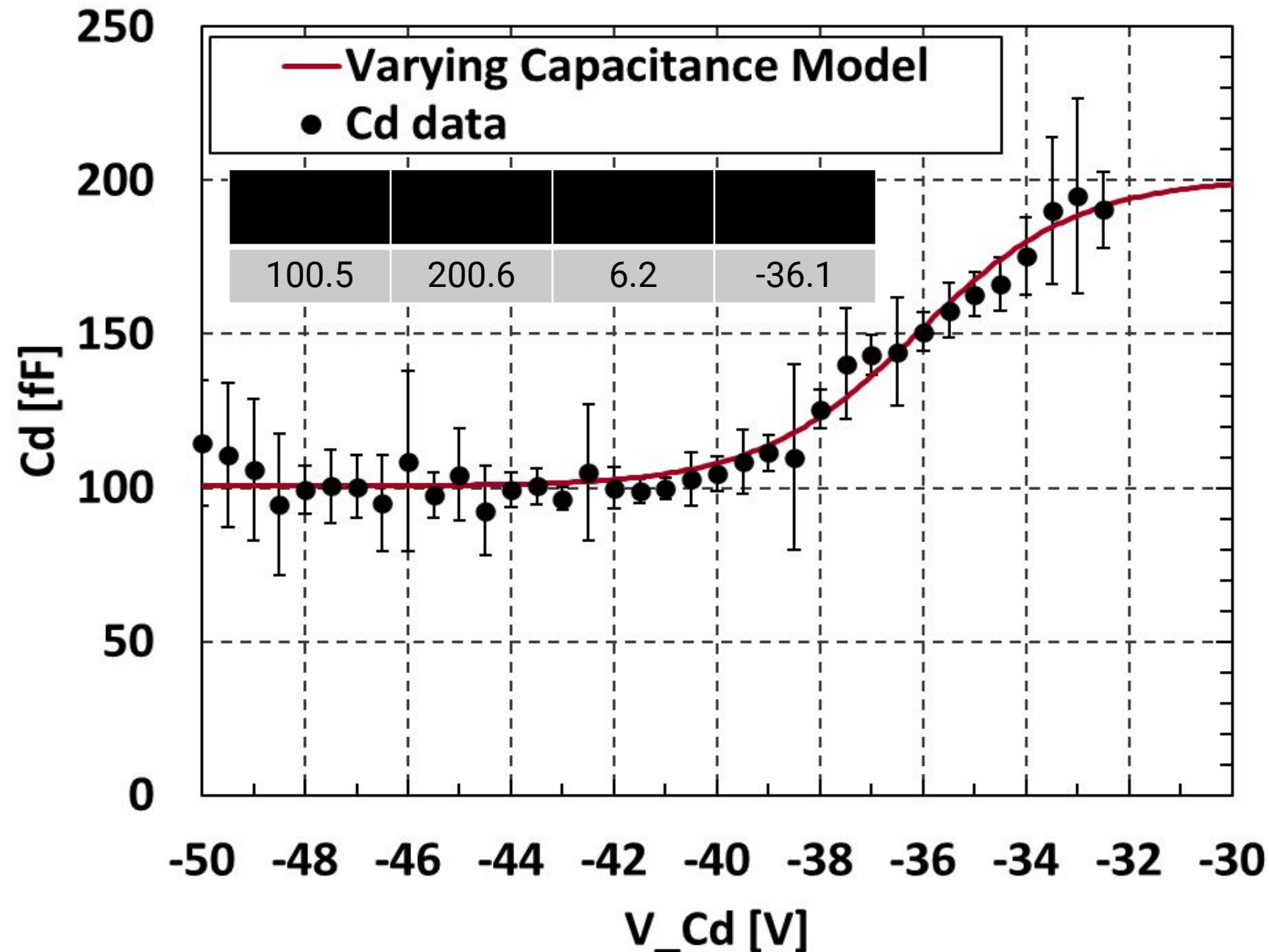
$$V = A \cdot e^{-\frac{t}{\tau_d}}$$

for each excess bias. Then

$$(C_d + C_q) = \frac{\tau_d}{R_q}$$

Electrical parameters extraction

Voltage varying capacitance model



- Assuming $C_q \approx 10fF$
- Model based on the hyperbolic tangent (sigmoid-like function) can be used

$$C(V_{bias}) = \frac{C_0 - C_{sat}}{2} \left(1 - \tanh \frac{2(V_{bias} - V_{th})}{V_{tra}} \right) + C_{sat}$$

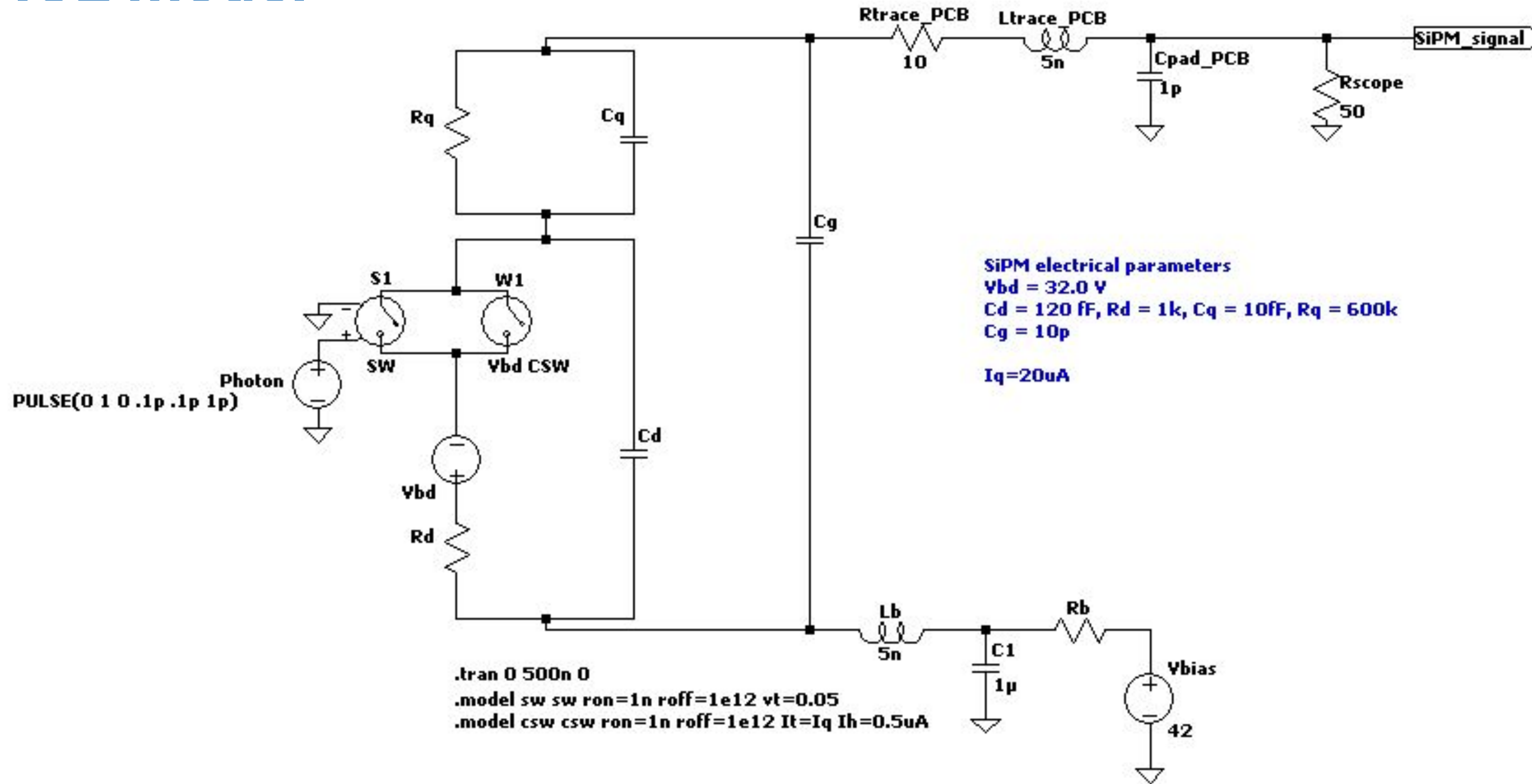
Reiner Bidenbach, RAQ Issue 192: "How to Use LTspice Simulations to Account for the Effect of Voltage Dependence", AnalogDialogue

SPAD signal electrical simulations

SPICE simulations

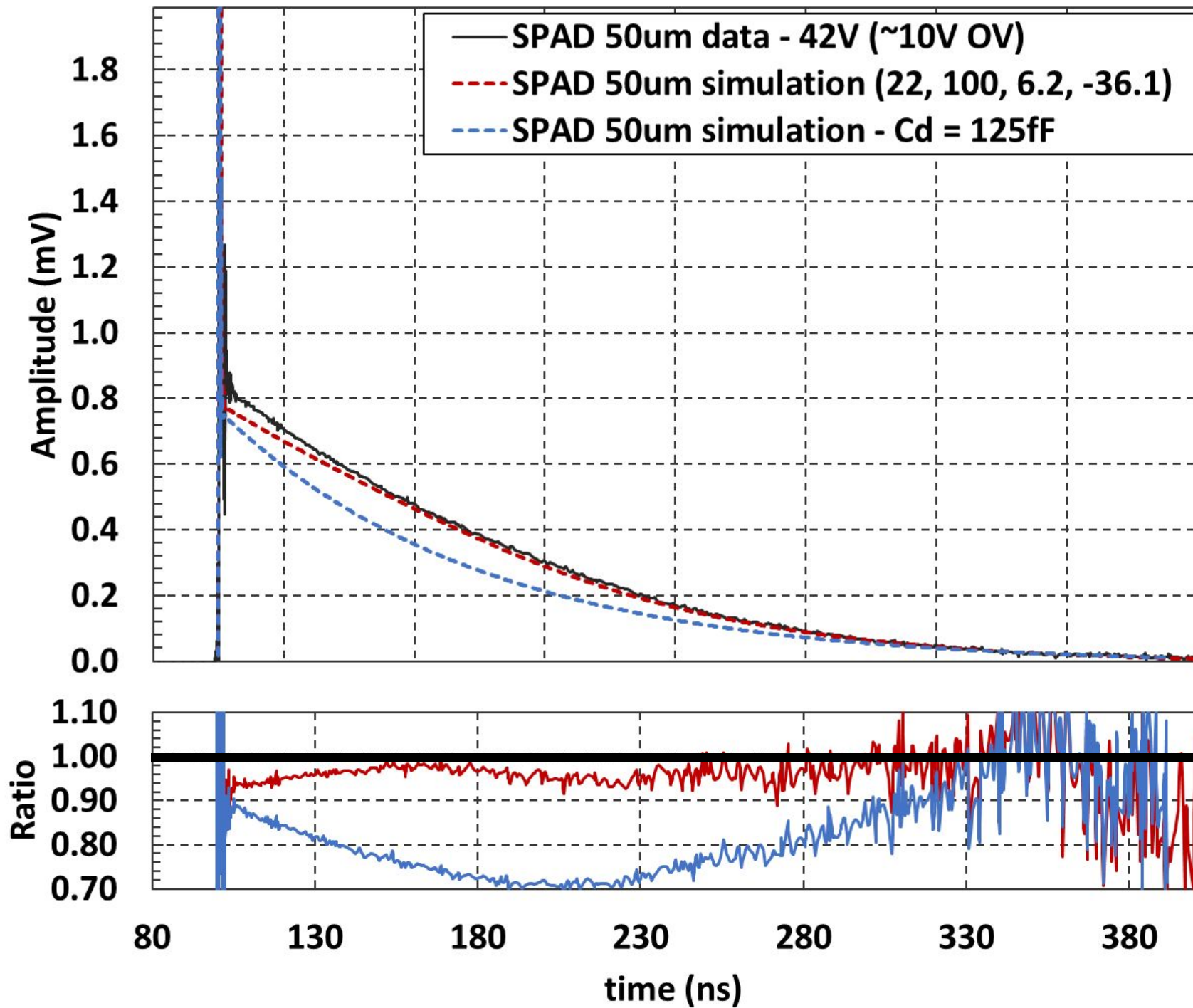
SPICE simulations

SPICE model



SPICE simulations

Simulation vs experimental data



- Comparison between a **constant capacitance** model and the **voltage varying capacitance** model
- The improved model **fits the experimental data** within the **~5%** discrepancy

Conclusion

...next step

Improved SPICE model

- A **50 μm SPAD** response was studied
 - Simulations **fits the experimental data** within the **~5%** discrepancy, using the varying capacitance model

FBK NUV-HD-MT SiPMs timing performance

- FBK NUV-HD MT technology shows an excellent SPTR (HF readout was used)
 - SPAD 40 μm M0: $(19.1 \pm 0.2) \text{ ps}$
 - SiPM 1x1mm² 40 μm M0: $(29.0 \pm 0.3) \text{ ps}$
 - SiPM 3x3mm² 40 μm M0: $(50.7 \pm 0.5) \text{ ps}$
 - SiPM 4x4mm² 40 μm M0: $(59.2 \pm 0.4) \text{ ps}$

...next steps

- Include the entire SiPM model in the model
- Implement the amplification stages in the model
- Run timing performance simulations
- Investigate the worsening of the SPTR with the increasing of the SPAD cell size
 - Focused SPTR



